

## Summary of Complete Solution for Video RAM

### 4.9.7.

The entire set of programs and files needed to test and GFI troubleshoot the Video RAM functional block is shown below. The format below is similar to a 9100A/9105A UUT directory (you could consider the functional block to be a small UUT), but in addition shows the use of each program and the location in this manual for each file.

#### UUT DIRECTORY (Complete File Set for Video RAM)

##### Programs (PROGRAM):

TST_VCTRL	Functional Test	Section 4.9.5
LEVELS	Stimulus Program	Figure 4-92
VIDEO_RDY	Stimulus Program	Figure 4-90
VIDEO_SCAN	Stimulus Program	Figure 4-77
VIDEO_INIT	Initialization Program	Figure 4-79
VIDEO_FIL1	Initialization Program	Figure 4-80
VIDEO_FIL2	Initialization Program	Figure 4-81

##### Stimulus Program Responses (RESPONSE):

LEVELS	Figure 4-93
VIDEO_RDY	Figure 4-91
VIDEO_SCAN	Figure 4-78

##### Node List (NODE):

NODELIST	Appendix B
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##### Text Files (TEXT):

VID_FILL1	Initialization Data File
VID_FILL2	Initialization Data File

##### Reference Designator List (REF):

REFLIST	Appendix A
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##### Compiled Database (DATABASE):

GFIDATA	Compiled by the 9100A
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**BUS BUFFER FUNCTIONAL BLOCK**

4.10.

**Buses and Bus Buffers**

4.10.1.

In addition to the bus at the pins of a microprocessor, many microprocessor-based designs include additional internal buses connecting the microprocessor, memory, I/O devices, and other circuitry. These internal buses are often separated by buffers or latches which complicate testing and troubleshooting.

For purposes of testing and troubleshooting, a bus is a group of signals that operate in an identical manner, such as an address or data bus. The bus is a connection between a *sending* output and one or more *receiving* inputs. For internal buses, the sending and receiving components may be buffers. Buffers separate internal buses from the microprocessor bus. A fault such as two buffered address lines tied together cannot be directly detected from the microprocessor bus. Thus, some faults on the buffered bus may go undetected by the built-in BUS TEST.

The key to testing a bus is that while there may be multiple outputs to the bus, only one should be active at any time. Each bus has an associated set of control and status lines which must also be tested.

**Considerations for Testing and Troubleshooting**

4.10.2.

There are several methods of testing bus buffers. For buses, it is usually desirable to test all combinations of bus signal levels to verify that:

- All lines are drivable.
- No two lines are shorted together.
- No lines are open between the master and the receivers.

This is particularly desirable for data and address buses, whose lines are often physically adjacent. These lines may be subject to manufacturing defects and failure modes, such as:

- Over-etching of traces causing open lines.
- Under-etching of traces causing shorted lines.
- Solder bridges causing shorted lines.
- Faulty or damaged parts causing lines to be stuck or open.
- Faulty or damaged parts that have incorrect logical behavior.

### Bus and Buffer Testing Capabilities

A ramp function is useful for testing buses and their associated buffers. The ramp function is a binary progression (i.e. a sequence of ascending numbers) covering all combinations of signal values. The ramp counts through all the values, starting at the lowest and ending at the highest. For large groups of signals, ramping over the full range can take considerable time. A means of ramping through a limited range by selecting a group of bits via a mask is therefore provided. For example, a 32-bit address bus may be covered by performing four ramping operations for each set of 8 bits (each group of which is probably associated with a particular buffer). This requires only  $4 \times 28$  or 1024 operations vs.  $2^{32}$  or 4.3 billion operations!

To troubleshoot a bus effectively, ramping operations must cover all normal transitions for logically adjacent lines. In the example above, suppose ramping operations covered address lines A0 through A7, A8 through A15, etc. If A7 and A8 are tied, the fault may not be discovered. It is therefore advisable to overlap ramping operations in order to provide the additional fault coverage. A portion of a TL/1 stimulus program might look like this:

```
rampaddr addr $F0000000, mask $1FF
rampaddr addr $F0000000, mask $1FF00
rampaddr addr $F0000000, mask $1FF0000
rampaddr addr $F0000000, mask $FF000000
```

There would be  $3 \times 2^9 + 2^8$  or 1792 iterations vs. 1024 in the preceding example. Overlapping ramp functions usually takes little additional test time.

Several built-in ramp and toggle stimulus functions are available: In TL/1, the commands are *rampaddr*, *rampdata*, *toggleaddr*, *toggledata*, and *togglecontrol* (see Section 3 of the *TL/1 Reference Manual*). From the operator's keyboard, the STIM key provides these functions (see Section 5 of the *Technical User's Manual*).

As described earlier in Section 2.2, the 9100A/9105A can make five types of measurements to determine whether a node is good or bad. The list below describes how these five measurement types relate to bus buffers. The combination of *CRC signatures* and *asynchronous level history* is recommended for most bus node measurements, except when data buses are being measured. Data buses are bidirectional and can be set to high-impedance levels between valid data times. In this case, CRC signatures with synchronous level history are the recommended measurement combination.

- *CRC signatures* are useful when associated with stimulus functions, since a unique signature results from a relatively large number of signal transitions. For a given stimulus program, two nodes that are tied will almost always have the same signature, different from the known-good signature.
- *Asynchronous level history* is useful when trying to determine whether a bus node is stuck. In this mode, the probe or I/O module will report all of a node's three states during the measurement period: logic 1, logic 0, or invalid X (high-impedance). Asynchronous level history is very useful for detecting glitches (short pulses) and is usually used together with CRC signatures. It should not, however, be used on data buses, which are bidirectional

and can be set to high impedance; since three-state conditions are not predictable on such lines, they may cause the measurement to fail. To measure data buses, use synchronous level history with CRC signatures.

- *Synchronous (clocked) level history* is used to measure signal levels at clock edges. This is useful for separation of signals present at the specified clock edges from signals present at other times. Clocked level history reports logic states in the same way as asynchronous level history. Measure data buses with this method, using the stable clock to avoid the three-state condition.
- *Transition count* is used in place of CRC signatures when there is no stable clock available.
- *Frequency* can be used to measure periodic bus cycles, such as refresh, or to verify the frequency of system clocks.

### Address Buffers

When troubleshooting address buffers, the physical address map of the UUT can be used to partition address buffer tests. For example, a set of address lines may be part of the I/O memory and associated with a particular buffer. Thus, a *rampaddr* command over the specific I/O memory range may be sufficient to verify proper operation of the buffer.

Other examples of address-bus partitions are:

- *Mapped address lines* are the microprocessor address lines that are translated or mapped into another set of lines by a fast RAM or VLSI component.
- *System bus address lines* are the address lines (usually different from the microprocessor address lines) in the system bus. These are usually buffered independently from internal address lines.
- *Internal (local) address lines* are usually buffered separately for local memory or other components.

Address lines may be latched as well as buffered. In latched applications, the latch acts as a buffer and should therefore be included in the Bus Buffer functional block.

### Data Buffers

Many UUTs with 16- and 32-bit microprocessors and standard buses have separate buffers for each group of eight bits with three-state and direction-control lines that can be controlled independently. There may also be buffers that allow swapping or repositioning of bytes within a word. The *rampdata* command, combined with CRC signatures, can be used to diagnose data-bus-related errors in a similar way as *rampaddr*.

The *rampdata* command is a stimulus with the microprocessor as the node source. To apply stimulus in the opposite direction, read data from a component on the bus (such as RAM, ROM or DMA). To do this, write a stimulus program to read data from the component, and record signatures in the same way as for *rampdata*. A ROM is a convenient component since, once programmed, it contains a pseudo-random pattern which, over a given address range, will generate meaningful signatures for the individual data lines. There is usually a ROM associated with each byte of the data bus. The *read* or *rampaddr* commands will provide the addresses for generating the data to be read from the ROM.

### Control Buffers

Control lines may sometimes be generated by an LSI component associated with the microprocessor. The LSI component is included here in the bus buffer functional block because it performs a function similar to the bus buffer. The testing and troubleshooting of these components proceeds as though they were simple buffers.

A faulty control buffer can cause the address-bus and data-bus tests to fail. Control signals are tested by performing reads and

writes in all possible address spaces and all possible data widths. Some control signals can be tested by the *togglecontrol* command. The control buffers should be checked as the control lines are stimulated.

Several types of control lines present problems. Here are some general guidelines:

- *Bus exchange* signals are used to relinquish control of the microprocessor bus to another master. Large systems may have a bus arbitration circuit for granting the bus to a requesting component. These circuits should probably be treated separately from the bus buffer block. Asynchronous access to the bus during tests should be restricted and access should be limited to the specific master acting as the stimulus source. The state of the bus-request line can be determined with the measurement techniques described above.
- *Direction control* signals control the direction of data flow through the buffers and are usually connected directly to inputs on the buffer ICs. These signals may be derived from microprocessor status lines, LSI components, or buffered versions of the microprocessor signal. There may also be separate read and write signals for different physical memory or I/O address spaces. The logic state for each of these signals should be verified for the appropriate bus cycle.
- *Wait-state control* signals such as READY on the 80286 microprocessor and  $\sim$ DTACK on the 68000 microprocessor extend the bus cycle to accommodate slower components. Stuck wait-state control lines will cause bus-related functions to fail. If the pod is the stimulus source, a stuck high (negated) condition on Ready will cause a pod timeout. When the pod timeout occurs, a message like "enabled line  $\sim$ READY PIN 63 causes timeout" (when using an 80286 pad) will result. The line can be disabled and testing can proceed. For example, when a ROM requiring one wait state is the stimulus source and the Ready or  $\sim$ DTACK signal is stuck low (asserted), the bus cycles may be completed but bad

data may be produced. As with other control lines, asynchronous level history is useful in detecting stuck control lines.

- *Reset* is a system-wide control signal which may be included in the bus buffer functional block. A reset signal stuck in the asserted state will probably affect many tests. Often, the only way to verify operation of a Reset signal without cycling the power on the UUT is to externally assert the signal using a switch, or overdriving device such as the probe. The various nodes which distribute the reset signal via buffers may be verified using the asynchronous level history measurement.

### Miscellaneous Lines

System clocks are sometimes associated with the control lines for a particular bus. These clocks are often used to synchronize external events with a bus cycle, they are often an integral part of control-signal generation, and they can cause control-signal faults if they are faulty.

Clocks asynchronous with the microprocessor clock are sometimes used to run state machines associated with bus- and buffer-control circuitry. Nodes that distribute these clocks via buffers can be measured with the probe or I/O module programmed to measure frequency. There is no stimulus associated with these frequency measurements, even though a stimulus program is used to set the mode on the measurement device. The same is true for the program used to measure asynchronous levels. These programs are referred to as response-only stimulus programs. See the *levels* and *frequency* programs in Section 4.8.6 and 4.12.6.

Pull-up or pull-down resistors which establish static logic levels on buses when there are no active outputs should also be tested. Levels can be verified with asynchronous level history measurements.



### VLSI Components

Some VLSI components integrate a large amount of peripheral microprocessor circuitry associated with personal computer designs, including the bus buffers. Operation of these components can be quite complex. To simplify stimulus program design, the buffer portion of these components, along with the associated control signals, can be grouped in a separate functional block from the other functions of the component. Testing can then be done in a manner similar to that for discrete buffers.

### Connectors

Connectors are a part of many bus buffering functional blocks. Whether these are test connectors, card-edge connectors or sockets, they are components that can cause stuck, tied, or open bus lines. Connectors should therefore be included in tests.

### Bus Buffer Example

#### 4.10.3.

The bus buffer in the Demo/Trainer UUT, Figure 4-96, uses an 82288 bus controller (U15) to decode status lines  $\sim S0$ ,  $\sim S1$ ,  $M/\sim IO$  from the microprocessor and to generate command signals for bus-cycle control. An "I" is appended to some mnemonics, signifying internal (buffered) signals. For example, data-bus lines D00-D15 become internal lines ID00-15.

The address bus (A00-23) is buffered with latches U2, U16, and U22. The rising edge of each ALE transition latches a new address.

For the data bus (D00-15), the 82288 outputs control signals DEN (data enable) and DT/ $\sim R$  (data transmit/receive). These two signals control the state of data-bus transceivers U23 and U3. For write cycles, both DEN and DT/ $\sim R$  are high. For read cycles, DEN is high and DT/ $\sim R$  is low.

**Keystroke Functional Test****4.10.4.****Part A:**

Use a 20-pin clip module on side A of I/O module 1 to test data and control outputs from the microprocessor. Use the SYNC, I/O MOD, and STIM keys with the commands below for each of the following parts: U3, U23, U22, U15, and U45. The correct measurement for each pin is shown in the response table in Figure 4-96.

```
SYNC I/O MOD 1 TO POD DATA
ARM I/O MOD 1 FOR CAPTURE USING SYNC
RAMP DATA 0 MASKED BY FF, ADDR 0
... (ADDR OPTION: I/O BYTE)
RAMP DATA 0 MASKED BY FF00, ADDR 0
... (ADDR OPTION: MEMORY WORD)
SHOW I/O MOD 1 PIN <see response table> ...
... CAPTURED RESPONSES
```

**NOTE**

*The SHOW command requires a clip module pin number rather than a part pin number. This requires you to translate part pin numbers to clip module pin numbers (see Appendix B of the Technical User's Manual). For your convenience, this translation has been done for you in this example, and the results are shown in the "I/O MOD PIN" column of the response table in Figure 4-96.*

**Part B:**

Use a 20-pin clip module on side A of I/O module 1 to test data input to the microprocessor from the ROMs. Use the SYNC, I/O MOD, and STIM keys with the commands below for U3 and then for U23. The correct measurement for each pin is shown in the response table in Figure 4-97.

```
SYNC I/O MOD 1 TO POD DATA
ARM I/O MOD 1 FOR CAPTURE USING SYNC
RAMP ADDR E0000 MASKED BY 1FE
... (ADDR OPTION: MEMORY WORD)
SHOW I/O MOD 1 PIN <see response table> ...
... CAPTURED RESPONSES
```

## Part C:

1. Use a 20-pin clip module on side A of I/O module 1 to test addresses and control outputs from the microprocessor.
2. Use the SETUP MENU key with the following commands to disable Ready so all addresses can be generated:

```
SETUP POD ENABLE ~READY OFF
SETUP POD REPORT FORCING SIGNALS OFF
```

3. Use the SYNC, I/O MOD, and STIM keys with the commands below for each of the following parts: U16, U2, U22, U15, and U45. The correct measurement for each pin is shown in response table #1 in Figure 4-98.

```
SYNC I/O MOD 1 TO POD ADDR
ARM I/O MOD 1 FOR CAPTURE USING SYNC
RAMP ADDR 0 MASKED BY FFC00
... (ADDR OPTION: MEMORY WORD)
RAMP ADDR 0 MASKED BY 7FF
... (ADDR OPTION: I/O BYTE)
SHOW I/O MOD 1 PIN <see response table> ...
... CAPTURED RESPONSES
```

4. Use the SYNC, I/O MOD, and STIM keys with the commands below for part U15. The correct measurement for each pin is shown in response table #2 in Figure 4-98.

```
SYNC I/O MOD 1 TO POD DATA
  (Note that this is pod DATA sync)
ARM I/O MOD 1 FOR CAPTURE USING SYNC
RAMP ADDR 0 MASKED BY FFC00
... (ADDR OPTION: MEMORY WORD)
RAMP ADDR 0 MASKED BY 7FF
```

```
... (ADDR OPTION: I/O BYTE)
SHOW I/O MOD 1 PIN 8 CAPTURED RESPONSES
SHOW I/O MOD 1 PIN 12 CAPTURED RESPONSES
```

5. After completing this functional test, use the SETUP MENU key with the commands below to enable Ready and to restore reporting of active forcing signals.

```
SETUP POD ENABLE READY ON
SETUP POD REPORT FORCING SIGNALS ON
```

### Part D:

Use a 20-pin clip module on side A of I/O module 1 to test control outputs during interrupt acknowledge by using the pod program named FRC\_INT. Use the SETUP MENU, SYNC, and I/O MOD keys with the commands below for U15 and then for U45. The correct measurement for each pin is shown in the response table in Figure 4-99.

```
SETUP POD ENABLE ~READY ON
SETUP POD REPORT FORCING SIGNALS ON
SETUP POD INTA_ACK ON
SYNC I/O MOD 1 TO POD INTA
ARM I/O MOD 1 FOR CAPTURE USING SYNC
POD: FRC_INT
... (ADDR OPTION: MEMORY WORD)
SHOW I/O MOD 1 PIN <see response table> ...
... CAPTURED RESPONSES
```

## Keystroke Functional Test (Part A)



CONNECTION TABLE

STIMULUS	MEASUREMENT
<div style="background-color: #FF69B4; width: 60px; height: 20px; margin: 0 auto; display: flex; align-items: center; justify-content: center;"> <span>POD</span> </div> <p>TEST ACCESS SOCKET</p>	<div style="background-color: #66CDAA; width: 80px; height: 20px; margin: 0 auto; display: flex; align-items: center; justify-content: center;"> <span>I/O MOD</span> </div> <p>U3      U15 U23    U45 U22</p>

RESPONSE TABLE

SIGNAL	PART PIN	I/O MOD PIN	SIGNATURE
ID00	U3-11	11	A A 6 1
ID01	-12	12	9 9 D F
ID02	-13	13	8 7 9 3
ID03	-14	14	E 6 1 8
ID04	-15	15	F 5 1 3
ID05	-16	16	4 F F B
ID06	-17	17	3 6 0 0
ID07	-18	18	B 2 5 9
ID08	U23-11		9 6 E C
ID09	-12	12	7 2 5 B
ID10	-13	13	E 5 E D
ID11	-14	14	5 B E 0
ID12	-15	15	7 E 2 5
ID13	-16	16	8 5 E A
ID14	-17	17	7 7 C 7
ID15	-18	18	6 E B E
ICOD/INTA	U22-5	5	F E A 2
IM/IO	-6	6	B B 3 4
WRITE	U15-9	9	F E A 2
IWRITE	-11	11	B B 3 4
DEN	-16	16	4 5 9 6
ALATCH	U45-8	14	4 5 9 6



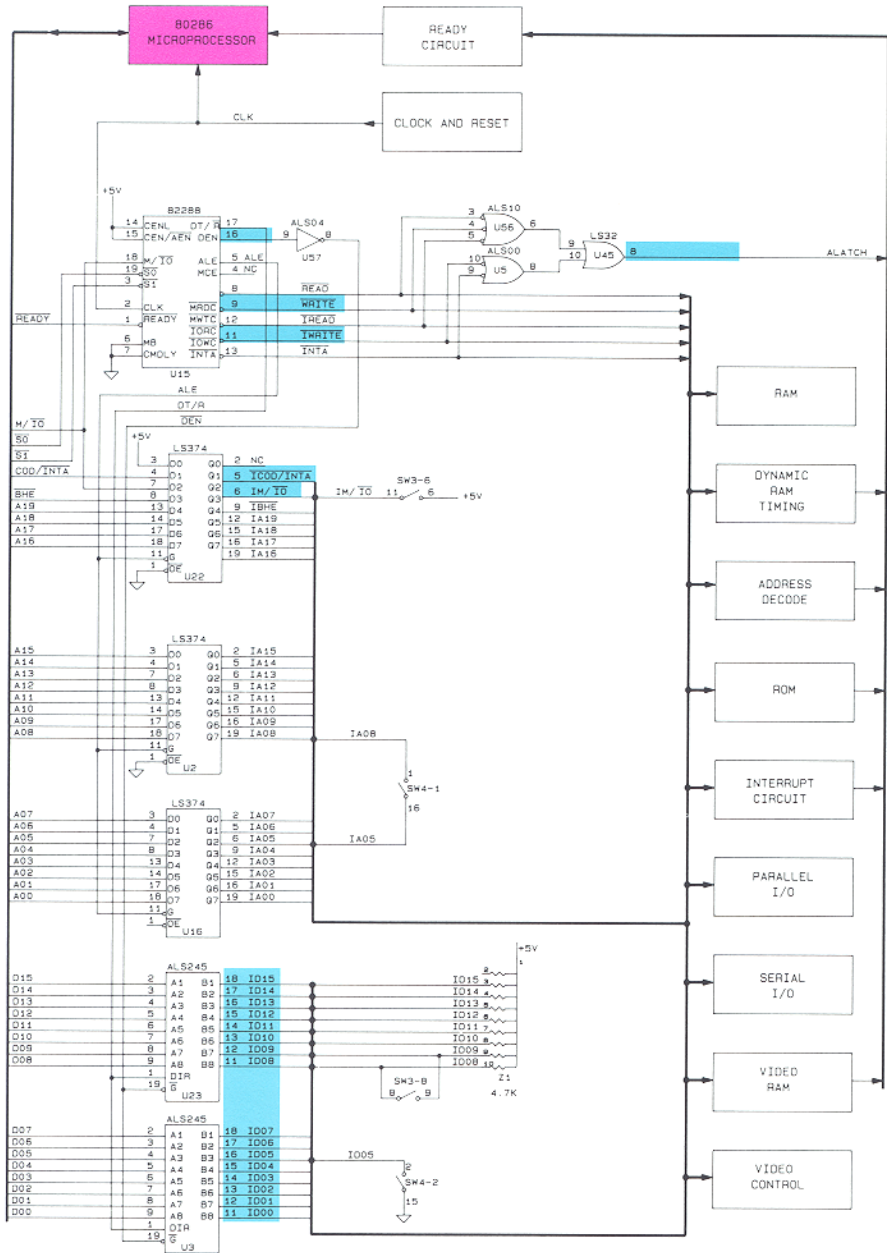


Figure 4-96: Bus Buffer Functional Test (Part A)

## Keystroke Functional Test (Part B)



CONNECTION TABLE

STIMULUS	MEASUREMENT
<div style="border: 1px solid black; background-color: #FF69B4; padding: 5px; width: fit-content; margin: 0 auto;">POD</div> <p>TEST ACCESS SOCKET</p>	<div style="border: 1px solid black; background-color: #66CDAA; padding: 5px; width: fit-content; margin: 0 auto;">I/O MOD</div> <p>U3 U23</p>

RESPONSE TABLE

SIGNAL	PART PIN	I/O MOD PIN	SIGNATURE
D00	U3-9	9	4 5 D D
D01	-8	8	C F 8 3
D02	-7	7	B D 7 9
D03	-6	6	8 A 7 6
D04	-5	5	6 6 F 3
D05	-4	4	F A B 5
D06	-3	3	5 3 4 E
D07	-2	2	8 D 0 A
D08	U23-9	9	7 3 E 9
D09	-8	8	A C 8 4
D10	-7	7	5 0 B B
D11	-6	6	5 B 3 B
D12	-5	5	0 6 E F
D13	-4	4	0 0 A 0
D14	-3	3	6 B F 0
D15	-2	2	5 2 E E



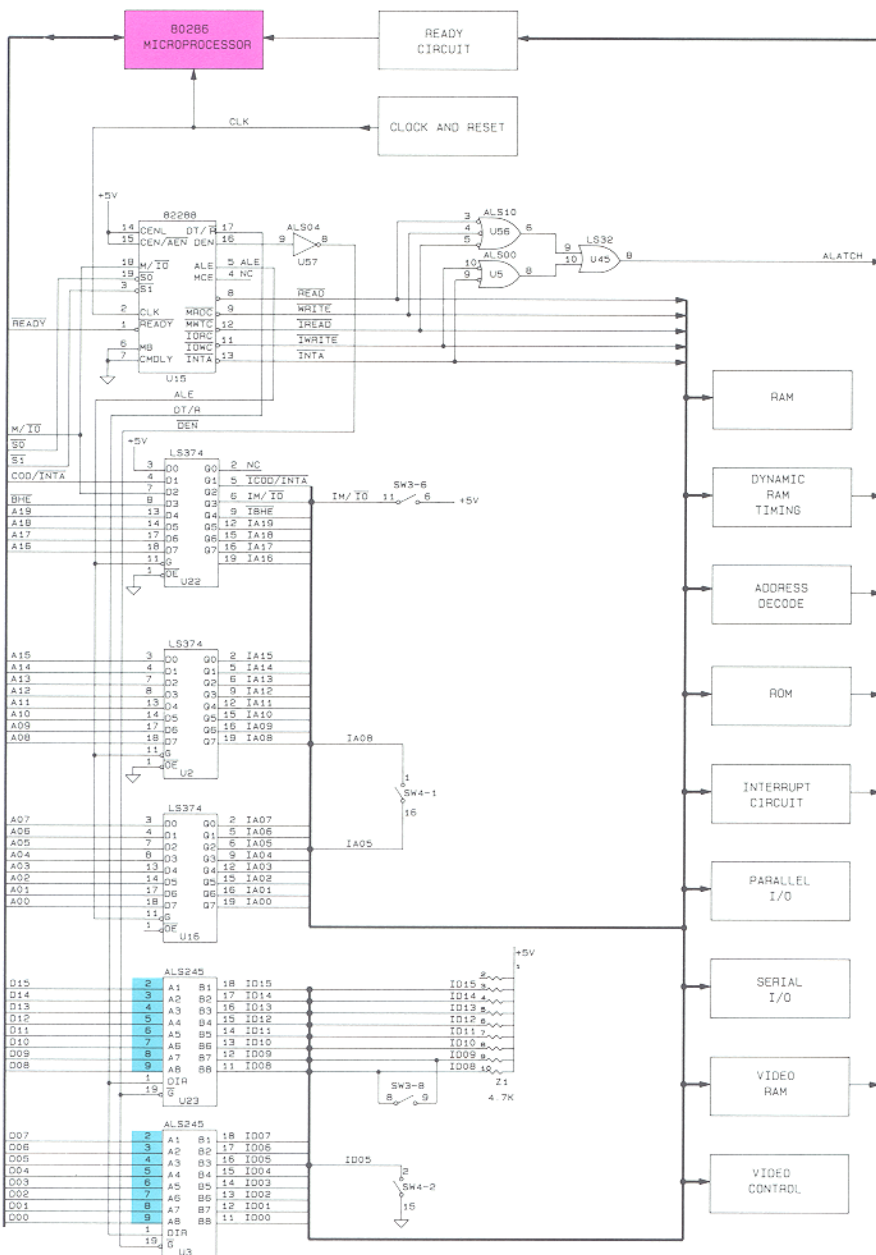


Figure 4-97: Bus Buffer Functional Test (Part B)



## Keystroke Functional Test (Part C)



CONNECTION TABLE

STIMULUS	MEASUREMENT
<div style="border: 1px solid black; width: 100px; height: 20px; background-color: #FF69B4; margin: 0 auto; display: flex; align-items: center; justify-content: center;"> <span style="color: white; font-weight: bold;">POD</span> </div> <p>TEST ACCESS SOCKET</p>	<div style="border: 1px solid black; width: 100px; height: 20px; background-color: #6495ED; margin: 0 auto; display: flex; align-items: center; justify-content: center;"> <span style="color: white; font-weight: bold;">I/O MOD</span> </div> <p>U16    U15 U2     U45 U22</p>

RESPONSE TABLE #1

SIGNAL	PART PIN	I/O MOD PIN	SIGNATURE	ASYNC LEVEL
IA00	U16-19	19	D 6 2 F	
IA01	-16	16	B 2 1 A	
IA02	-15	15	D A 0 7	
IA03	-12	12	1 0 2 4	
IA04	-9	9	E 0 3 0	
IA05	-6	6	4 4 4 2	
IA06	-5	5	4 F 2 A	
IA07	-2	2	0 7 7 2	
IA08	U2-19	19	9 6 3 5	
IA09	-16	16	1 7 3 4	
IA10	-15	15	4 1 B A	
IA11	-12	12	4 5 5 A	
IA12	-9	9	B E E D	
IA13	-6	6	3 8 6 8	
IA14	-5	5	D E E 6	
IA15	-2	2	C 2 6 5	
IA16	U22-19	19	F 8 A 7	
IA17	-16	16	9 1 9 6	
IA18	-15	15	2 5 E 4	
A19	-12	12	4 A 7 4	
IBHE	-9	9	A C 5 F	
ALE	U15-5	5	2 A 4 2	1 0
INTA	-13	5	2 A 4 2	1
DT/R	-17	17	9 D 9 2	1 0
ALATCH	U45-8	14	B 7 D 0	1 0

RESPONSE TABLE #2

SIGNAL	PART PIN	I/O MOD PIN	SIGNATURE
READ	U15-8	8	4 5 1 3
IREAD	-12	12	6 F 5 1

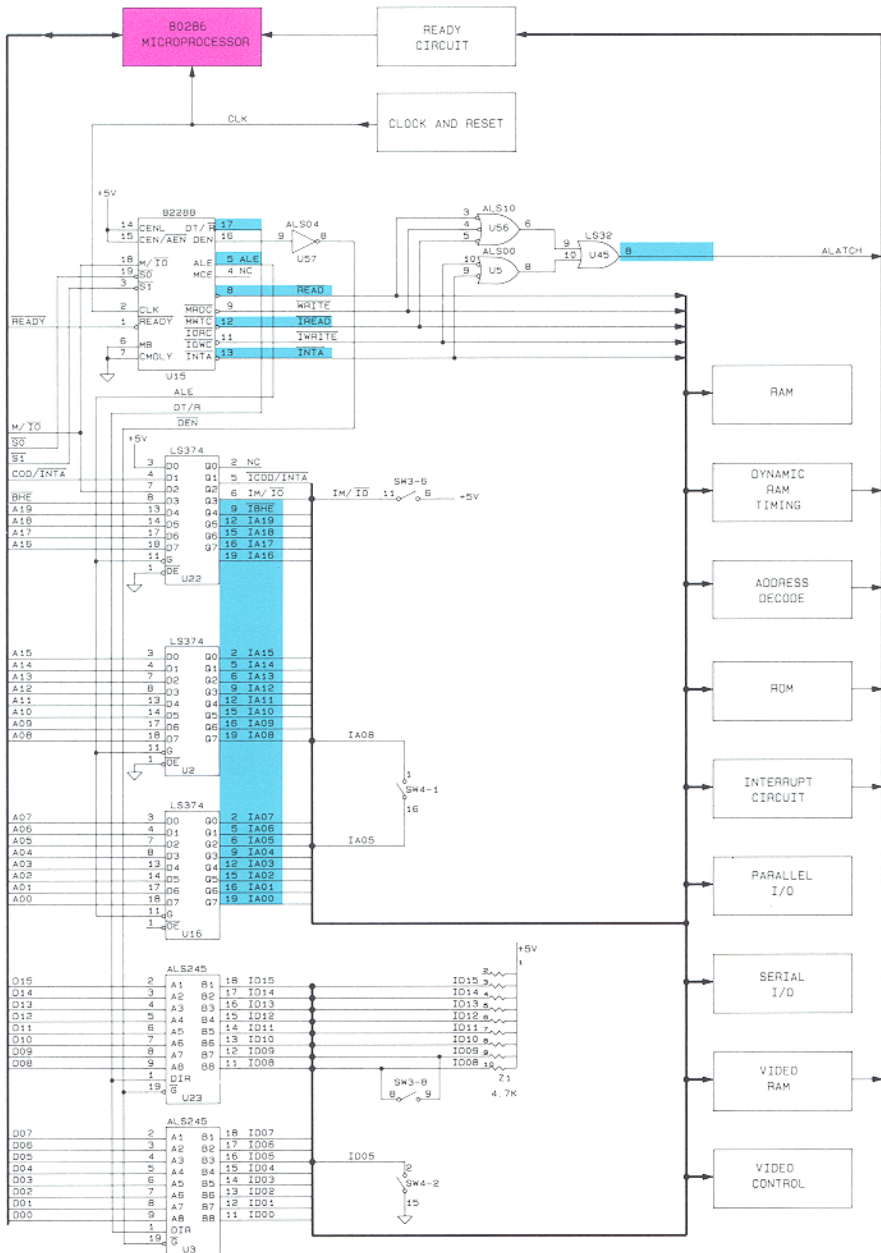


Figure 4-98: Bus Buffer Functional Test (Part C)

## Keystroke Functional Test (Part D)



CONNECTION TABLE

STIMULUS	MEASUREMENT
<div style="background-color: #ff69b4; padding: 5px; display: inline-block; margin-bottom: 5px;">POD</div> TEST ACCESS SOCKET	<div style="background-color: #add8e6; padding: 5px; display: inline-block; margin-bottom: 5px;">I/O MOD</div> U15 U45 U22

RESPONSE TABLE

SIGNAL	PART PIN	I/O MOD PIN	SIGNATURE
ALE	U15-5	5	0 0 0 0
READ	-8	8	0 0 0 1
WRITE	-9	9	0 0 0 1
IWRITE	-11	11	0 0 0 1
IREAD	-12	12	0 0 0 1
INTA	-13	13	0 0 0 0
DT/R	-17	17	0 0 0 0
ALATCH	U45-8	14	0 0 0 1
ICOD/INTA	U22-5	5	0 0 0 0



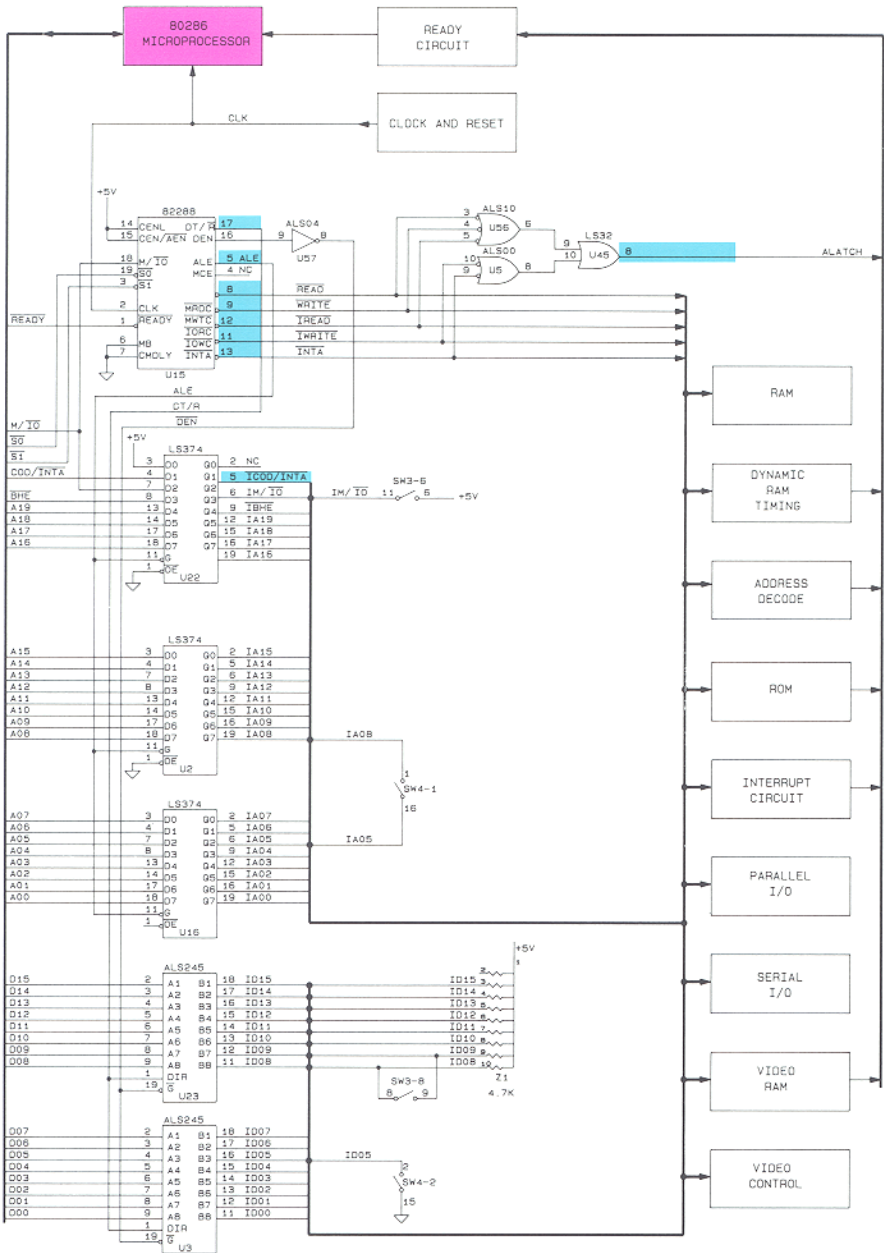


Figure 4-99: Bus Buffer Functional Test (Part D)

# Programmed Functional Test

## 4.10.5.

The *tst\_buffer* program is the programmed functional test for the Bus Buffer functional block. The *gfi\_test* command is used to run all stimulus programs defined for the parts tested and to compare the results against known-good responses stored in the response files. If all results are good, the *gfi\_test* passes; otherwise the *gfi\_test* fails.

The *tst\_buffer* program performs a *gfi\_test* on address buffer U16. If the *gfi\_test* fails, a program called *abort\_test* is executed using a variable containing the part and pin number that was tested by the *gfi\_test* command. A listing for the *abort\_test* program is included in Appendix C.

The *abort\_test* program uses the *gfi\_accuse* command to see if an accusation exists. If there is no accusation, a *gfi\_hint* containing the part number and pin number is generated and the program is terminated (the *gfi\_hint* gives GFI a place to start troubleshooting). If an accusation does exist, the *abort\_test* program displays the accusation and the program is terminated.

The *gfi\_test* (and execution of *abort\_test* if the *gfi\_test* fails) is repeated for the other two address buffers U2 and U22 and then for the data bus buffers U3 and U23.

```

program tst_buffer
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! FUNCTIONAL TEST of the BUS BUFFER functional block.                                !
!                                                                                     !
! This program tests the BUS BUFFER functional block of the                         !
! Demo/Trainer. The gfi test command and I/O module are used to clip               !
! over the buffers and perform the test.                                           !
!                                                                                     !
! TEST PROGRAMS CALLED:                                                              !
!   abort_test (ref-pin)                                                             !
!                                                                                     !
!                                                                                     !
!                                                                                     !
!                                                                                     !
!                                                                                     !
!                                                                                     !
!                                                                                     !
!                                                                                     !
!                                                                                     !
!                                                                                     !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

```

```
print "\n!TESTING BUS BUFFER Circuit"

! Test ADDRESS BUS

    if gfi test "U16-1" fails then abort_test("U16-1")
    if gfi test "U2-1" fails then abort_test("U2-1")
    if gfi test "U22-1" fails then abort_test("U22-1")

! Test DATA BUS

    if gfi test "U3-1" fails then abort_test("U3-1")
    if gfi test "U23-1" fails then abort_test("U23-1")

print "BUS BUFFER TEST PASSES"
end program
```

## Stimulus Programs and Responses

### 4.10.6.

Figure 4-100 is the stimulus program planning diagram for the Bus Buffer functional block.

The stimulus programs *addr\_out*, *ctrl\_out1*, *ctrl\_out2*, *ctrl\_out3*, and *data\_out* exercise outputs going outward from the microprocessor. The *rom1\_data* stimulus program stimulates the outputs of the data buffers that are connected to the microprocessor.

## Stimulus Program Planning



<b>PROGRAM: ADDR_OUT</b>
EXERCISES ALL ADDRESS LINES FROM THE MICROPROCESSOR
<b>MEASUREMENT AT:</b> U16-19,16,15,12,9,6,5,2 U2-19,16,15,12,9,6,5,2 U22-19,16,15,12,9

<b>PROGRAM: CTRL_OUT2</b>
EXERCISES CONTROL LINES FROM THE MICROPROCESSOR USING DATA SYNCHRONIZATION
<b>MEASUREMENT AT:</b> U15-17,8,9,12,11,13,5 U56-6 U45-8 U5-8

<b>PROGRAM: DATA_OUT</b>
EXERCISES ALL DATA LINES AS OUTPUTS FROM THE MICROPROCESSOR
<b>MEASUREMENT AT:</b> U3-11,12,13,14,15,16,17,18 U23-11,12,13,14,15,16,17,18

<b>PROGRAM: CTRL_OUT3</b>
EXERCISES CONTROL LINES FROM THE MICROPROCESSOR USING INTERRUPT ACKNOWLEDGE SYNCHRONIZATION
<b>MEASUREMENT AT:</b> U15-17,5,8,9,12,11,13 U56-6 U45-8 U5-8

<b>PROGRAM: CTRL_OUT1</b>
EXERCISES CONTROL LINES FROM THE MICROPROCESSOR USING POD ADDRESS SYNCHRONIZATION
<b>MEASUREMENT AT:</b> U22-5,6 U57-8 U15-16 U45-8

<b>PROGRAM: ROM1_DATA</b>
EXERCISES ALL DATA LINES AS INPUTS TO THE MICROPROCESSOR
<b>MEASUREMENT AT:</b> U3-9,8,7,6,5,4,3,2 U23-9,8,7,6,5,4,3,2



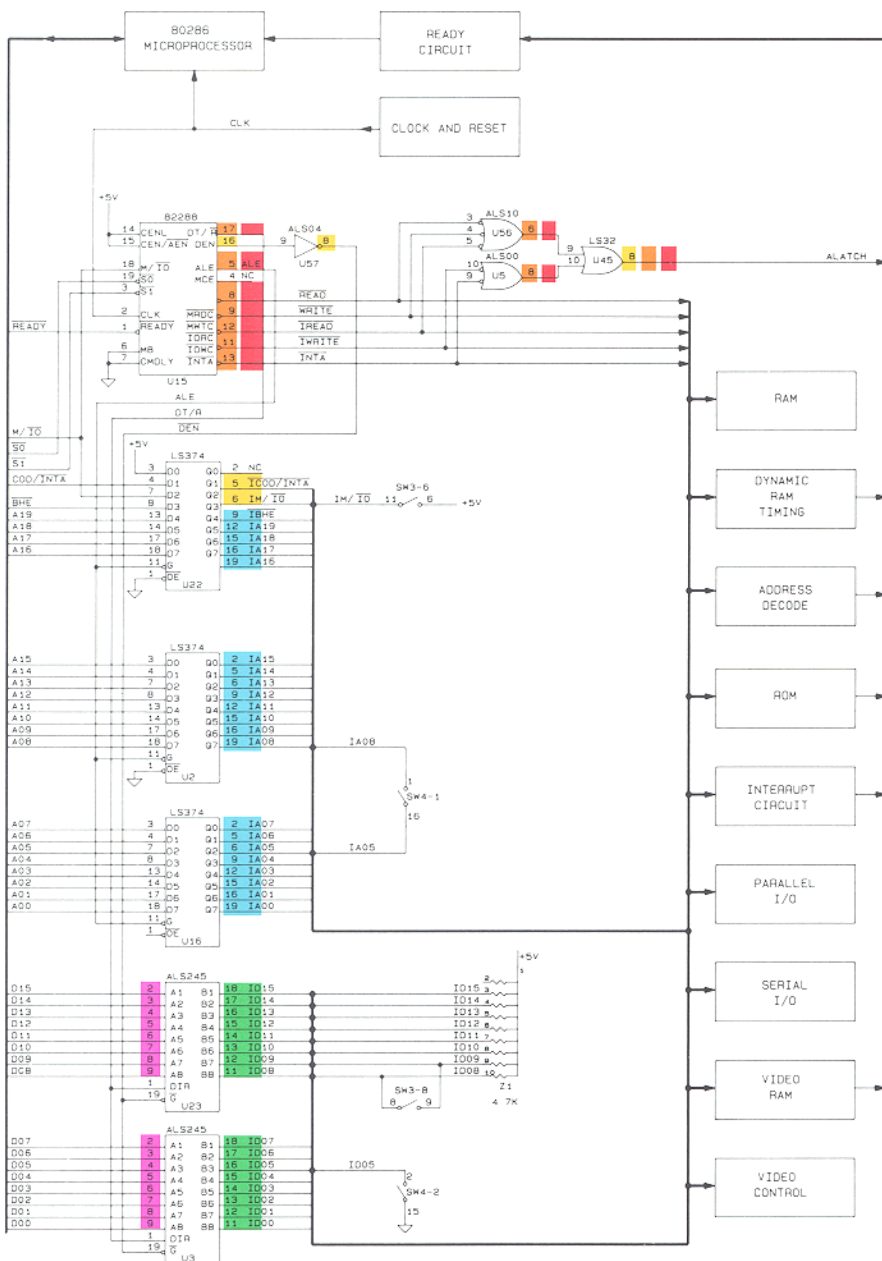


Figure 4-100: Bus Buffer Stimulus Program Planning



```
program ctrl_out2

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! STIMULUS PROGRAM for bus controller, U15 & uP ctrl lines.                !
!                                                                            !
! Stimulus programs and response files are used by GFI to backtrace        !
! from a failing node. The stimulus program must create repeatable UUT    !
! activity and the response file contains the known-good responses for    !
! the outputs in the UUT that are stimulated by the stimulus program.     !
!                                                                            !
! This stimulus program is one of the programs which creates activity      !
! in the kernel area of the UUT. These programs create activity with     !
! or without the ready circuit working properly. Because of this, all    !
! the stimulus programs in the kernel area must disable the READY input  !
! to the pod, then perform the stimulus, then re-enable the READY input  !
! to the pod. The 80286 microprocessor has a separate bus controller;    !
! for this reason, disabling ready and performing stimulus can get the    !
! bus controller out of synchronization with the pod. Two fault          !
! handlers trap pod timeout conditions that indicate the bus controller  !
! is out of synchronization. The recover() program is executed to       !
! resynchronize the bus controller and the pod.                            !
!                                                                            !
! TEST PROGRAMS CALLED:                                                    !
!   recover      ()               The 80286 microprocessor has a          !
!                               bus controller that is totally          !
!                               separate from the pod. In               !
!                               some cases the pod can get out          !
!                               of sync with the bus control-          !
!                               ler. The recover program                !
!                               resynchronizes the pod and the          !
!                               bus controller.                         !
!                               !                                       !
! GRAPHICS PROGRAMS CALLED:                                              !
!   (none)                                                         !
!                                                                            !
! Local Variables Modified:                                             !
!   devname                Measurement device                          !
!   io_byte                I/O BYTE address space                    !
!   mem_word               MEMORY WORD address space                 !
!   !                                                               !
! Global Variables Modified:                                           !
!   recover_times          Reset to Zero                             !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Main Declarations                                                    !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

declare global numeric recover_times
```

(continued on the next page)

Figure 4-101: Stimulus Program (ctrl\_out2)

```

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
!   FAULT HANDLERS:                                                                                                                                           !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

handle pod timeout_enabled_line
    recover()
end handle
handle pod timeout_recovered
    recover()
end handle
handle pod_timeout_no_clk
end handle

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
!   Main part of STIMULUS PROGRAM                                                                                                                           !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

recover_times = 0

! Let GFI determine the measurement device.

if (gfi control) = "yes" then
    devname = gfi device
else
    devname = "/mod1"
end if
print "Stimulus Program CTRL_OUT2"

! Set addressing mode and setup measurement device.

podsetup 'enable ~ready' "off"
podsetup 'report power' "off"
podsetup 'report forcing' "off"
podsetup 'report intr' "off"
podsetup 'report address' "off"
podsetup 'report data' "off"
podsetup 'report control' "off"
io_byte = getspace space "i/o", size "byte"
mem_word = getspace space "memory", size "word"
reset device devname
sync device devname,mode "pod"
sync device "/pod", mode "data"
old_cal = getoffset device devname
setoffset device devname, offset (1000000 - 70)

! Present stimulus to UUT.

arm device devname                ! Start response capture.
    setspace (mem_word)
    rampaddr addr $E0000, mask $1E
    rampdata addr $50000, data 0, mask $F
    setspace (io_byte)
    rampaddr addr 0, mask $5F00
    rampdata addr $2000, data 0, mask $F
readout device devname            ! End response capture.

setoffset device devname, offset old_cal
podsetup 'enable ~ready' "on"
end program

```

Figure 4-101: Stimulus Program (*ctrl\_out2*) - continued

# Bus Buffer

STIMULUS PROGRAM NAME: CTRL\_OUT2  
DESCRIPTION:

SIZE: 261 BYTES

Node Signal Src	Learned With	SIG	Response Data			Priority Pin
			Async LVL	Clk LVL	Counter Mode	
U15-5	I/O MODULE	0000	1	0	0	TRANS
U15-8	PROBE	A5B1	1	0		TRANS
U15-8	I/O MODULE	A5B1	1	0		TRANS
U15-9	PROBE	A841	1	0		TRANS
U15-9	I/O MODULE	A841	1	0		TRANS
U15-11	PROBE	448E	1	0		TRANS
U15-11	I/O MODULE	448E	1	0		TRANS
U15-12	PROBE	F383	1	0		TRANS
U15-12	I/O MODULE	F383	1	0		TRANS
U15-13	I/O MODULE	BAFD	1			TRANS
U15-17	I/O MODULE	ECFF	1	0		TRANS
U5-8	I/O MODULE	FE73	1	0		TRANS
U45-8	I/O MODULE	BAFD	1	0		TRANS
U56-6	PROBE	448E	1	0		TRANS
U56-6	I/O MODULE	448E	1	0		TRANS

Figure 4-102: Response File (*ctrl\_out2*)

```

program ctrl_out3

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! STIMULUS PROGRAM for bus controller, U15 & uP ctrl lines.           !
!                                                                       !
! Stimulus programs and response files are used by GFI to backtrace   !
! from a failing node. The stimulus program must create repeatable UUT !
! activity and the response file contains the known-good responses for !
! the outputs in the UUT that are stimulated by the stimulus program.  !
!                                                                       !
! This stimulus program is one of the programs which creates activity  !
! in the kernel area of the UUT. These programs create activity with  !
! or without the ready circuit working properly. Because of this, all  !
! the stimulus programs in the kernel area must disable the READY input !
! to the pod, then perform the stimulus, then re-enable the READY input !
! to the pod. The 80286 microprocessor has a separate bus controller;  !
! for this reason, disabling ready and performing stimulus can get the !
! bus controller out of synchronization with the pod. Two fault      !
! handlers trap pod timeout conditions that indicate the bus controller !
! is out of synchronization. The recover() program is executed to    !
! resynchronize the bus controller and the pod.                       !
!                                                                       !
! TEST PROGRAMS CALLED:                                               !
!   recover      ()        The 80286 microprocessor has a          !
!                         bus controller that is totally!
!                         separate from the pod. In        !
!                         some cases the pod can get out!
!                         of sync with the bus control-   !
!                         ler. The recover program        !
!                         resynchronizes the pod and the!
!                         bus controller.                 !
!                                                                       !
!   frc_int      ()        Pod program to Force Interrupt!
!                         Ack.                             !
!                                                                       !
! GRAPHICS PROGRAMS CALLED:                                           !
!   (none)                                                   !
!                                                                       !
! Local Variables Modified:                                           !
!   devname        Measurement device                         !
!   io_byte        I/O BYTE address space                   !
!   mem_word       MEMORY WORD address space                !
!                                                                       !
! Global Variables Modified:                                           !
!   recover_times  Reset to Zero                           !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

```

(continued on the next page)

Figure 4-103: Stimulus Program (*ctrl\_out3*)

## Bus Buffer

---

```
! Let GFI determine the measurement device.

if (gfi control) = "yes" then
    devname = gfi device
else
    devname = clip ref "U15"
end if
print "Stimulus Program CTRL_OUT3"

! Set addressing mode and setup measurement device.

io_byte = getspace space "i/o", size "byte"
mem_word = getspace space "memory", size "word"
podsetup 'report power' "off"
podsetup 'report forcing' "off"
podsetup 'report intr' "off"
podsetup 'report address' "off"
podsetup 'report data' "off"
podsetup 'report control' "off"
reset device devname
podsetup 'intr_ack on'
sync device "/pod", mode "inta"
sync device devname, mode "pod"

! Present stimulus to UUT.

arm device devname           ! Start response capture.
execute frc_int()           ! Force Interrupt Ack.
readout device devname       ! End response capture.

end program
```

Figure 4-103: Stimulus Program (*ctrl\_out3*) - *continued*

STIMULUS PROGRAM NAME: CTRL\_OUT3  
 DESCRIPTION:

SIZE: 282 BYTES

Node Signal Src	Learned With	SIG	Response Data			Counter Range	Priority Pin
			Async	Clk	Counter		
U15-5	I/O MODULE	0000	1	0	TRANS		
U15-8	PROBE	0001	1	0	TRANS		
U15-8	I/O MODULE	0001	1	0	TRANS		
U15-9	PROBE	0001	1		TRANS		
U15-9	I/O MODULE	0001	1		TRANS		
U15-11	PROBE	0001	1		TRANS		
U15-11	I/O MODULE	0001	1		TRANS		
U15-12	PROBE	0001	1		TRANS		
U15-12	I/O MODULE	0001	1		TRANS		
U15-13	I/O MODULE	0000	1	0	TRANS		
U15-17	I/O MODULE	0000	1	0	TRANS		
U4-3	I/O MODULE	0000	1	0	TRANS		
U5-8	I/O MODULE	0001	1	0	TRANS		
U45-8	I/O MODULE	0001	1	0	TRANS		
U56-6	PROBE	0000	1	0	TRANS		
U56-6	I/O MODULE	0000	1	0	TRANS		
U15-4	I/O MODULE	0000	1	0	TRANS		

Figure 4-104: Response File (ctrl\_out3)

**Summary of Complete Solution for Bus Buffer****4.10.7.**

The entire set of programs and files needed to test and GFI troubleshoot the Bus Buffer functional block is shown below. The format below is similar to a 9100A/9105A UUT directory (you could consider the functional block to be a small UUT), but in addition shows the use of each program and the location in this manual for each file.

**UUT DIRECTORY**  
(Complete File Set for Bus Buffer)

**Programs (PROGRAM):**

TST_BUFFER	Functional test	Section 4.10.5
ADDR_OUT	Stimulus Program	Figure 4-4
DATA_OUT	Stimulus Program	Figure 4-6
CTRL_OUT1	Stimulus Program	Figure 4-8
CTRL_OUT2	Stimulus Program	Figure 4-101
CTRL_OUT3	Stimulus Program	Figure 4-103
ROM1_DATA	Stimulus Program	Figure 4-16

**Stimulus Program Responses (RESPONSE):**

ADDR_OUT	Figure 4-5
DATA_OUT	Figure 4-7
CTRL_OUT1	Figure 4-9
CTRL_OUT2	Figure 4-102
CTRL_OUT3	Figure 4-104
ROM1_DATA	Figure 4-17

**Node List (NODE):**

NODELIST	Appendix B
----------	------------

**Text Files (TEXT):****Reference Designator List (REF):**

REFLIST	Appendix A
---------	------------

**Compiled Database (DATABASE):**

GFIDATA	Compiled by the 9100A
---------	-----------------------

**ADDRESS DECODE FUNCTIONAL BLOCK**

**4.11.**

**Introduction to Address Decode Circuits**

**4.11.1.**

The Address Decode circuit of a UUT typically consists of the decoder ICs, an address path from the microprocessor to the decoder ICs, and the decoder outputs that select the peripheral devices on the UUT. Figure 4-105 shows such a circuit.

Many microprocessor systems contain an address latch or a buffer between the microprocessor and the address decoder ICs. The decoder ICs generally contain combinatorial logic that asserts one and only one of the decoder outputs for a given range of addresses. The address decoder typically has one or more enable input pins. The signals feeding these pins may be address lines or outputs from other decoders.

In some cases, the address decode logic is just one part of an LSI chip. In this situation, the LSI component should be partitioned so that only those inputs and outputs that relate to address decoding are part of the Address Decode functional block.

**Considerations for Testing and Troubleshooting**

**4.11.2.**

Use the 9100A/9105A's I/O module to test address decoding circuits. The general procedure is to characterize all decoder ICs and paths in the address decoding circuit of a known-good UUT, and then perform the same procedures on the suspect UUT, comparing results.

For each decoder IC in the circuit, the following test procedure can be used from the operator's keypad:

1. Clip the I/O module onto the IC.
2. Synchronize and arm the I/O module (see the *Technical User's Manual* for this procedure).



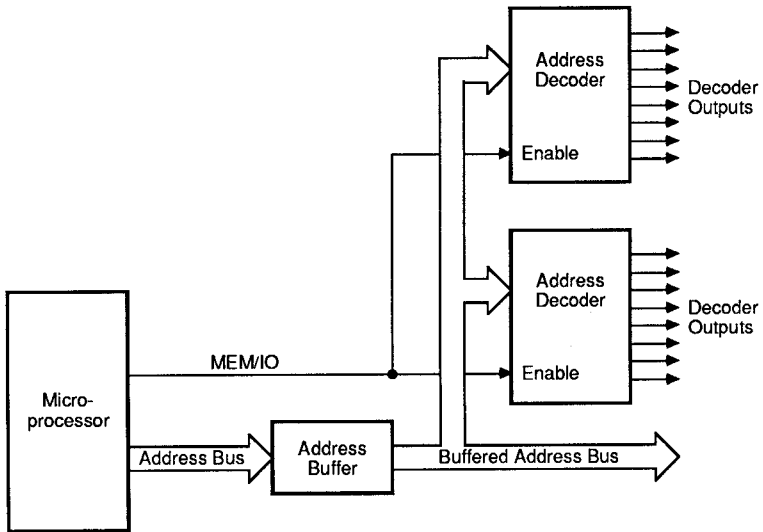


Figure 4-105: Typical Address Decode Functional Block

3. Run a stimulus procedure to make each output go high and low.
4. Use the SHOW I/O MOD command on the I/O MOD key (operator's keypad) to observe signatures on each pin of the IC.
5. Write down the signatures gathered from each pin on the IC, both inputs and outputs.

Since decoder outputs are typically asserted only over a specific address range, your stimulus procedure should also perform its reads and writes within that range for each decoder output. For example, consider a decoder with eight outputs, as follows:

<i>Decoder Output</i>	<i>Address Range (hex)</i>
~Y0	0-7FF
~Y1	800-FFF
~Y2	1000-17FF
~Y3	1800-2FFF
~Y4	3000-37FF
~Y5	3800-3FFF
~Y6	4000-47FF
~Y7	4800-4FFF

A stimulus procedure to test the first output, ~Y0, might consist of the following:

```
READ ADDR 0
READ ADDR 7FF
```

This will test the end points of the valid address range for ~Y0, to verify that ~Y0 is asserted (low) within that range. The same pair of reads within the valid address range of ~Y1 will test that ~Y0 is not asserted (high) outside the valid address range of ~Y0. You can use this strategy to test all of the decoder outputs with only 16 read operations.

If the outputs of a decoder IC are bad and the inputs are good, suspect the IC and/or suspect shorts on the output signal paths. If the decoder inputs are bad as well, trace back toward the microprocessor. If your UUT has address latches or buffers, perform a similar test on them.

Watch for decoder ICs that are enabled only during reads or writes. Use the appropriate stimulus command (*read* or *write*) on these ICs.

### Address Decode Circuit Example

### 4.11.3.

Figure 4-106 shows the address decode circuit (U8, U9, and U21) in the Demo/Trainer UUT. It selects the memory or I/O component being addressed. Some of the buffered address lines and bus controller lines are used to enable the following decoded address output lines (all have active low outputs):

<i>Output</i>	<i>Address Range Enabled</i>	<i>Circuit Enabled</i>
RAM0	00000-0FFFF	64K byte dynamic RAM
RAM1	10000-1FFFF	64K byte dynamic RAM
VRAM	20000-2FFFF	Video RAM
IPOLL	30000-3FFFF	Interrupt polling
SPARE1	40000-4FFFF	(decode complete signal)
SPARE2	50000-5FFFF	(decode complete signal)
ROM0	E0000-EFFFF	64K byte ROM, U29 and U30
ROM1	F0000-FFFFF	64K byte ROM, U27 and U28
VIDSLT	00000-01FFE	Video controller
I/OSLT	02000-03FFE	RS-232 port and the ASCII keyboard
PPISLT	04000-05FFE	Outputs to seven-segment displays and inputs from test switches S1 through S4

## Keystroke Functional Test

## 4.11.4.

1. Use a 16-pin clip module on side A of I/O module 1 to test the decoded signals.
2. Use the SETUP MENU key with the commands below:

```
SETUP POD ENABLE ~READY OFF
SETUP POD REPORT FORCING SIGNALS OFF
```

3. Use the SYNC, I/O MOD, and STIM keys with the commands below for each of the following parts: U8, U9 and U21. The correct measurements for each pin are shown in the response table in Figure 4-106.

```
SYNC I/O MOD 1 TO POD DATA
ARM I/O MOD 1 FOR CAPTURE USING SYNC
RAMP ADDR 0 MASKED BY F0000
... (ADDR OPTION: MEMORY WORD)
RAMP ADDR 0 MASKED BY F000
... (ADDR OPTION: I/O BYTE)
SHOW I/O MOD 1 PIN <see response table> ...
... CAPTURED RESPONSES
```

**NOTE**

*The SHOW command requires a clip module pin number rather than a part pin number. This requires you to translate part pin numbers to clip module pin numbers (see Appendix B of the Technical User's Manual). For your convenience, this translation has been done for you in this example, and the results are shown in the "I/O MOD PIN" column of the response table in Figure 4-106.*

4. After completing the test, use the SETUP MENU key with the commands below to restore the settings for POD ENABLE and POD REPORT:

SETUP POD ENABLE READY ON  
SETUP POD REPORT FORCING SIGNALS ON

(This page is intentionally blank.)

## Keystroke Functional Test



### CONNECTION TABLE

STIMULUS	MEASUREMENT
<div style="border: 1px solid black; width: 100px; height: 20px; background-color: #FF69B4; margin: 0 auto; display: flex; align-items: center; justify-content: center;"> <span style="color: white; font-weight: bold;">POD</span> </div> <p>TEST ACCESS SOCKET</p>	<div style="border: 1px solid black; width: 100px; height: 20px; background-color: #66CDAA; margin: 0 auto; display: flex; align-items: center; justify-content: center;"> <span style="color: white; font-weight: bold;">I/O MOD</span> </div> <p>U8 U9 U21</p>

### RESPONSE TABLE

SIGNAL	PART PIN	I/O MOD PIN	SIGNATURE
RAM0	U8-15	19	9 C A 8
RAM1	U8-14	18	6 B A D
VRAM	U8-13	17	9 0 2 F
IPOLL	U8-12	16	6 D E E
SPARE1	U8-11	15	9 3 0 E
SPARE2	U8-10	14	6 C 7 E
ROM0	U9-9	13	3 C 7 B
ROM1	U9-7	7	3 B 4 C
VIDSLT	U21-15	19	F 8 B E
I/OSLT	U21-14	18	0 9 2 A
PPISLT	U21-13	17	3 5 4 F



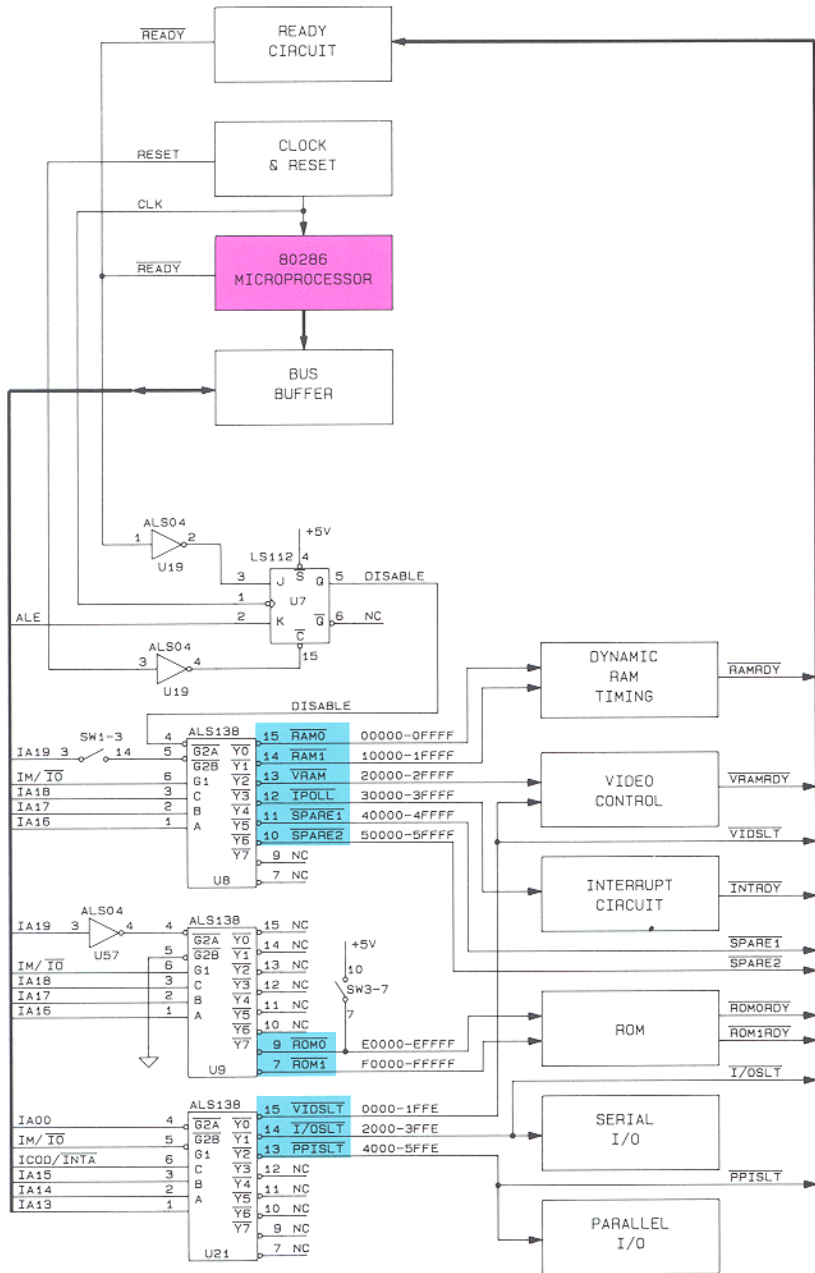


Figure 4-106: Address Decode Functional Test



Programmed Functional Test

4.11.5.

The *tst\_decode* program is the programmed functional test for the Address Decode functional block. This program checks the three address decode ICs (U8, U9 and U21) using the *gfi test* command. If the *gfi test* command fails, the *abort\_test* program is executed and GFI troubleshooting begins. (See the Bus Buffer functional block for a discussion of the *abort\_test* program).

```

program tst_decode

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! FUNCTIONAL TEST of the DECODE functional block.                               !
!                                                                              !
! This program tests the DECODE functional block of the Demo/Trainer.          !
! The gfi test command and I/O module are used to clip over the decoders!    !
! and perform the test.                                                         !
!                                                                              !
! TEST PROGRAMS CALLED:                                                         !
!   abort_test (ref-pin)                If gfi has an accusation              !
!                                       display the accusation else            !
!                                       create a gfi hint for the              !
!                                       ref-pin and terminate the test!        !
!                                       program (GFI begins trouble-          !
!                                       shooting).                             !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Main Declarations                                                             !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

declare
  global string decode_checked = ""      ! Record this test was run
end declare

if decode_checked <> "yes" then
  decode_checked = "yes"
  print "\n\n!TESTING ADDRESS DECODE"

  podsetup 'enable ~ready' "off"
  podsetup 'report forcing' "off"

  if gfi test "U8-15" fails then abort_test("U8-15")
  if gfi test "U9-7" fails then abort_test("U9-7")
  if gfi test "U21-15" fails then abort_test("U21-15")

  print "ADDRESS DECODE TEST PASSES"
end if
end program

```

**Stimulus Programs and Responses****4.11.6.**

Figure 4-107 is the stimulus program planning diagram for the Address Decode functional block. The *decode* stimulus program performs an access at each decoded address space. The *addr\_out* stimulus program exercises the address lines. The *reset\_low* stimulus program checks the reset signal when the test operator presses the Demo/Trainer UUT RESET pushbutton.

## Stimulus Program Planning



<b>PROGRAM: DECODE</b>
PERFORMS AN ACCESS FOR EACH DECODED BLOCK
<b>MEASUREMENT AT:</b> U8-15,14,13,12,11,10 U9-9,7 U21-15,14,13 U7-5 U19-2,4

<b>PROGRAM: RESET_LOW</b>
PROMPTS THE OPERATOR TO PRESS THE RESET KEY AND THEN CHECKS FOR A LOW LEVEL
<b>MEASUREMENT AT:</b> U19-4

<b>PROGRAM: ADDR_OUT</b>
EXERCISES ALL ADDRESS LINES FROM THE MICROPROCESSOR
<b>MEASUREMENT AT:</b> U57-4



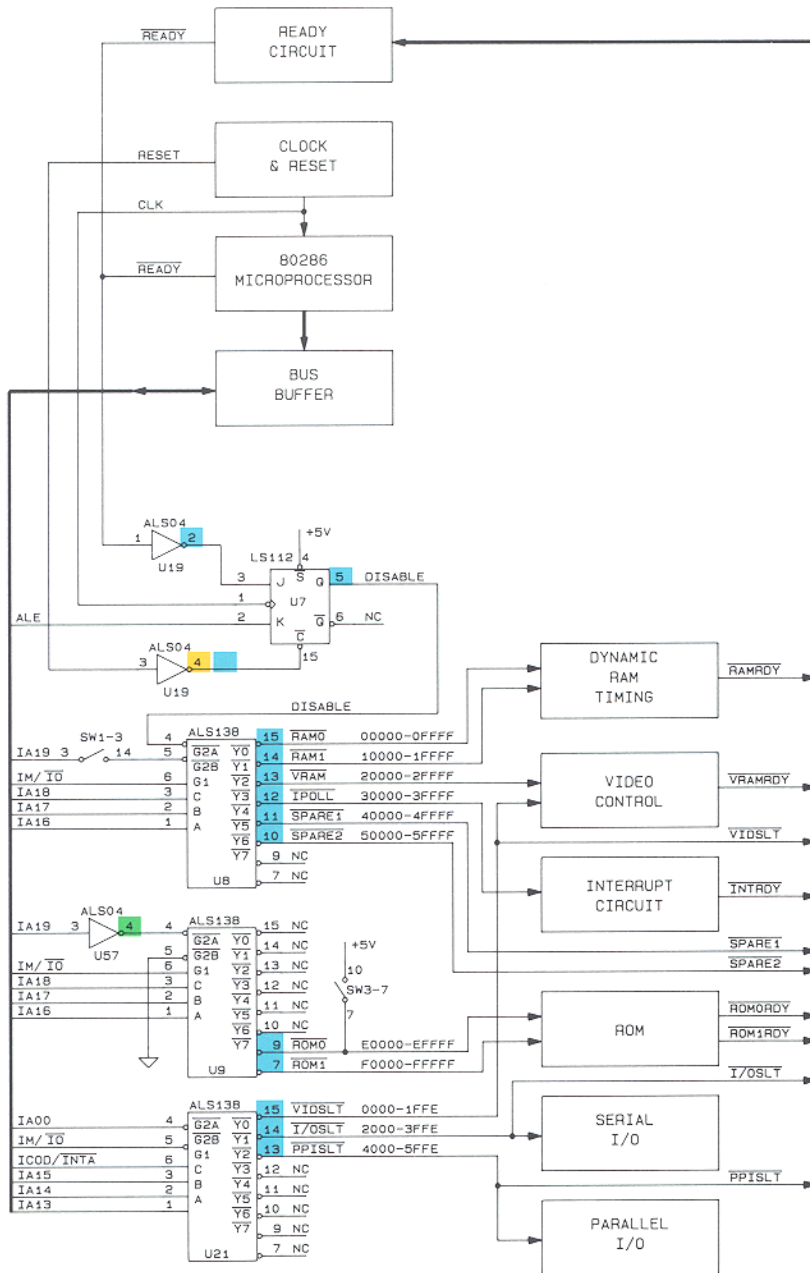


Figure 4-107: Address Decode Stimulus Program Planning





# Address Decode

STIMULUS PROGRAM NAME: DECODE  
DESCRIPTION:

SIZE: 392 BYTES

Node Signal Src	-----		Response Data -----			Priority Pin
	Learned With	SIG	Async	Clk	Counter	
			LVL	LVL	Mode	Counter Range
U8-15	I/O MODULE	03F9	1	0	TRANS	
U8-14	I/O MODULE	05F6	1	0	TRANS	
U8-13	I/O MODULE	06F1	1	0	TRANS	
U8-12	I/O MODULE	0772	1	0	TRANS	
U8-11	I/O MODULE	07B3	1	0	TRANS	
U8-10	I/O MODULE	07D3	1	0	TRANS	
U9-9	I/O MODULE	07E3	1	0	TRANS	
U9-7	I/O MODULE	07FB	1	0	TRANS	
U21-15	PROBE	07F7	1	0	TRANS	
U21-15	I/O MODULE	07F7	1	0	TRANS	
U21-14	PROBE	07F1	1	0	TRANS	
U21-14	I/O MODULE	07F1	1	0	TRANS	
U21-13	I/O MODULE	07F2	1	0	TRANS	
U7-5	I/O MODULE	0000	1	0	TRANS	
U19-2	I/O MODULE	0675	1	0	TRANS	
U19-4	I/O MODULE	07F3	1		TRANS	
U45-3	I/O MODULE	07FB	1	0	TRANS	
U45-6	I/O MODULE	07E3	1	0	TRANS	
U5-11	I/O MODULE	07F3	1		TRANS	
U4-3	I/O MODULE	07F3	1		TRANS	
U57-2	I/O MODULE	0637	1	0	TRANS	
U57-6	I/O MODULE	0081	1	0	TRANS	

Figure 4-109: Response File (decode)

## Summary of Complete Solution for Address Decode

4.11.7.

The entire set of programs and files needed to test and GFI troubleshoot the Address Decode functional block is shown below. The format below is similar to a 9100A/9105A UUT directory (you could consider the functional block to be a small UUT), but in addition shows the use of each program and the location in this manual for each file.

### UUT DIRECTORY (Complete File Set for Address Decode)

#### Programs (PROGRAM):

TST_DECODE	Functional Test	Section 4.11.5
DECODE	Stimulus Program	Figure 4-108
ADDR_OUT	Stimulus Program	Figure 4-4
RESET_LOW	Stimulus Program	Figure 4-115

#### Stimulus Program Responses (RESPONSE):

DECODE	Figure 4-109
ADDR_OUT	Figure 4-5
RESET_LOW	Figure 4-114

#### Node List (NODE):

NODELIST	Appendix B
----------	------------

#### Text Files (TEXT):

#### Reference Designator List (REF):

REFLIST	Appendix A
---------	------------

#### Compiled Database (DATABASE):

GFIDATA	Compiled by the 9100A
---------	-----------------------



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**CLOCK AND RESET FUNCTIONAL BLOCK**

4.12.

**Introduction to Clock and Reset Circuits**

4.12.1.

Microprocessor-system clock circuits may generate single periodic digital signals or multiple signals representing different phases of a single time base. Both types of clocks may be present in a UUT. Clock circuits typically include circuitry for buffering and/or dividing clock sources.

Reset circuits range in complexity from simple resistor-capacitor networks to several IC's. Often a single switch, IC, gate, or monostable multivibrator serves as the reset circuit. Some UUTs have watchdog timers which automatically reset the UUT if the microprocessor gets lost in a program.

**Considerations for Testing and Troubleshooting**

4.12.2.

**Clocks**

When clocks circuits fail, most other functional blocks will also fail. Clock problems are usually associated with only a few components. Here are some guidelines:

- *Open or stuck nodes* on the crystal oscillator. Manufacturing defects or failed components may cause stuck or open lines on ICs used as oscillators.
- *DC or capacitive loading* on the outputs of the oscillator. A stuck or tied line may load the oscillator output so that it cannot generate a signal.
- *Failed counter or flip-flop* deriving lower frequency signals from the master clock. Pullup or pulldown resistors establishing static logic levels on unused counter or flip-flop inputs may be short or open.

- *Failed clock-generator IC.* Clock generator ICs may fail due to manufacturing defects or shorted or tied inputs.

Frequency measurements with the probe or I/O module are a good way to trace clock-related problems. For measurements above 10 MHz, use the probe; measurements below that frequency can be made with the I/O module.

The Demo/Trainer UUT stimulus program called *frequency*, in Section 4.12.6, shows how to program the I/O module to measure frequency. The frequency of the clock is measured three times during a 9100A/9105A LEARN operation on a known-good UUT, when the response file is created. If the value of the clock is stable, a single decimal value is recorded. If the value of the clock is unstable, the highest and lowest values are recorded. With frequency or transition counts, the min-max range must be large enough to account for variations between UUTs and variations due to environmental factors, such as temperature and humidity. To establish the range, first learn the response from a known-good UUT, then adjust the range for appropriate tolerance factors.

Some clock-related problems, such as injected noise, marginal signals, or asymmetrical phases, are hard to detect with digital test equipment. The probe, which operates at up to 40 MHz, is very useful for these problems. Asynchronous level history measurements with the probe can detect marginal signal levels and noise. If, after measurements with the probe, the UUT still exhibits erratic clock behavior, check the quality of the clock signal with a high-bandwidth oscilloscope.

### Reset

Asynchronous level history is a useful measurement technique with which to verify the operation of a reset circuit.

Several 9100A/9105A devices are useful in detecting reset faults. The probe can be used to verify static logic levels on circuit nodes. The I/O module can be used to overdrive the Reset input to verify operation. Since most Reset lines connect

to the microprocessor, the pod can sense whether this line is active. In setting up test fixturing, it is helpful to connect the Reset line to a test point or test connector attached to an I/O module line. This allows the test program to automatically reset the UUT at the start of a test sequence.

Verify operation of the Reset line in both states. The Demo/Trainer UUT stimulus programs called *reset\_low* and *reset\_high*, in Section 4.12.6, show how the probe and I/O module can be used to troubleshoot reset circuits.

For reset circuits that use a switch or pushbutton, the operator must usually be involved. A prompt to the operator can be displayed, asking that the switch be pressed during certain modes of the test while measurements are performed.

### Clock and Reset Example

### 4.12.3.

The clock source in the Demo/Trainer UUT is a 31.9399 MHz oscillator (U18). This frequency is divided by two and by four. The 8 MHz signal is used by the 82284 clock generator (U1) to generate the microprocessor clock signals. The 31.9399 MHz signal is also used in the Video Ready generation circuit.

The 15.9799 MHz signal is used as the clock source for the video circuit. The Reset signal is controlled by the RESET pushbutton switch. Pressing this switch causes an active Ready signal to be generated.

### Keystroke Functional Test

4.12.4.

#### Part A:

Measure frequency of clock signals with the probe, using the PROBE and SOFT KEYS key with the command below:

FREQ AT PROBE =

The pins to be probed and the correct measurements at each pin are shown in the response table in Figure 4-110.

#### Part B:

Operate the RESET switch and measure the level of U1-12 with the probe, using the PROBE and SOFT KEYS key with the command below:

INPUT PROBE LEVEL =

The pins to be probed and the correct measurements at each pin are shown in the response table in Figure 4-111.

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## Keystroke Functional Test (Part A)



CONNECTION TABLE

STIMULUS	MEASUREMENT
(NONE)	<div style="border: 1px solid black; background-color: #ADD8E6; padding: 5px; width: fit-content; margin: 0 auto;">PROBE</div> <p>U1 U25</p>

RESPONSE TABLE

SIGNAL	PART PIN	FREQUENCY	
		MINIMUM	MAXIMUM
CCLK	U1-10	7.995 MHZ	8.000 MHZ
PCLK	U1-13	3.997 MHZ	4.000 MHZ
16 MHZ	U25-9	15.99 MHZ	16.00 MHZ
32 MHZ	U25-13	31.98 MHZ	32.00 MHZ



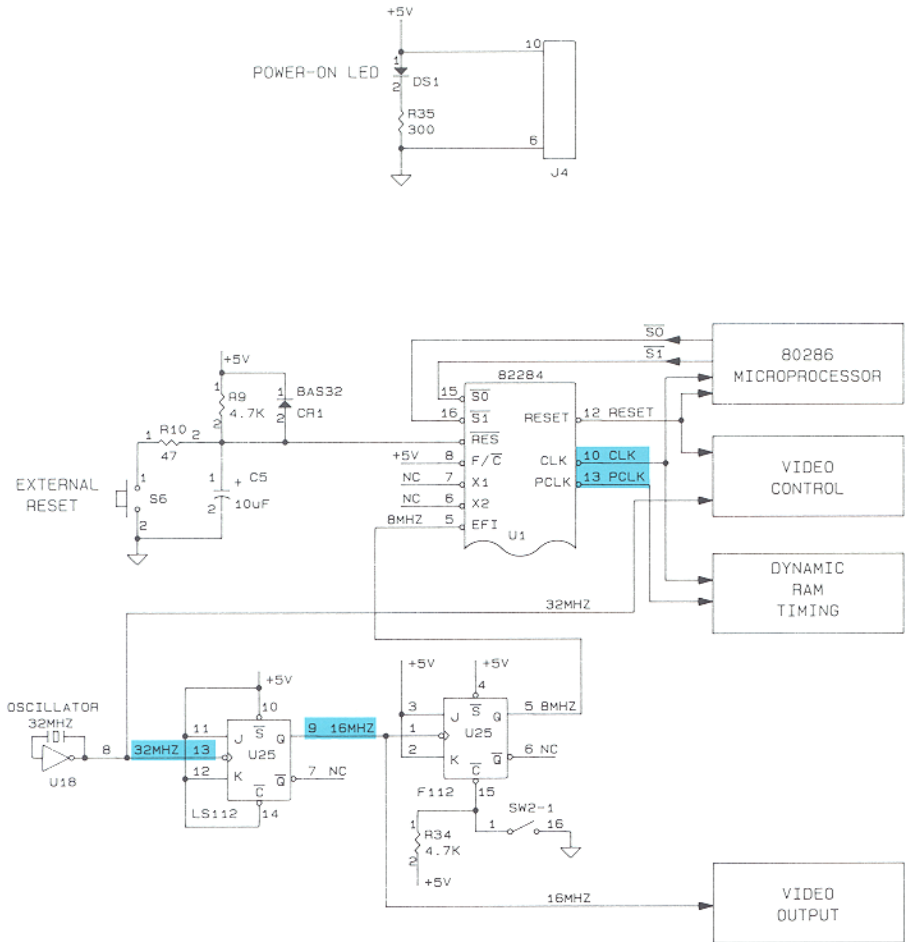


Figure 4-110: Clock and Reset Functional Test (Part A)



## Keystroke Functional Test (Part B)



CONNECTION TABLE

STIMULUS	MEASUREMENT
<div data-bbox="219 343 450 399" style="border: 1px solid black; padding: 5px; margin: 10px auto; width: fit-content;">RESET SWITCH</div> <p data-bbox="324 423 346 440" style="text-align: center;">S6</p>	<div data-bbox="703 343 871 399" style="border: 1px solid black; padding: 5px; margin: 10px auto; width: fit-content;">PROBE</div> <p data-bbox="765 423 810 440" style="text-align: center;">U1-12</p>

STIMULUS AND RESPONSE TABLE

RESET SWITCH	PART PIN	LEVEL
<p data-bbox="216 638 300 676" style="text-align: center;">RELEASED PRESSED</p>	<p data-bbox="534 638 587 676" style="text-align: center;">U1-12 U1-12</p>	<p data-bbox="838 638 884 676" style="text-align: center;">LOW HIGH</p>

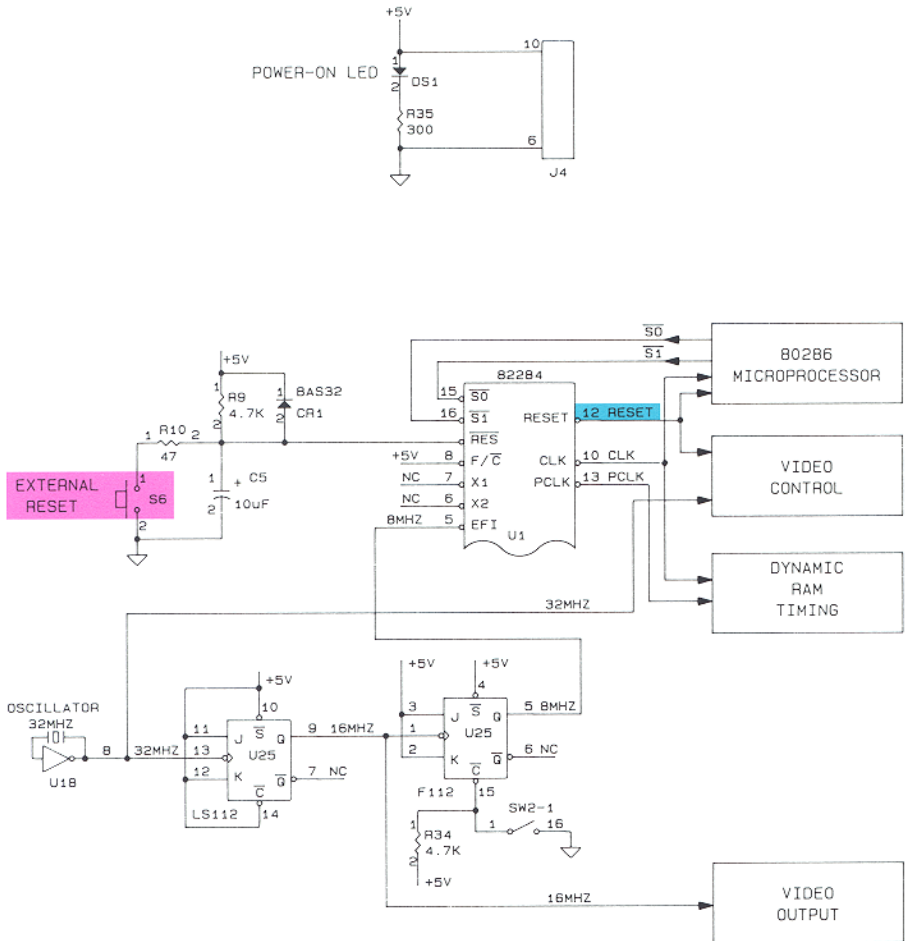


Figure 4-111: Clock and Reset Functional Test (Part B)

## Programmed Functional Test

## 4.12.5.

The *tst\_clock* program is the programmed functional test for the Clock and Reset functional block. U1 is a signal conditioning IC for the Clock, Reset, and Ready signals, however the *tst\_clock* program tests only the Clock and Reset portion of the chip.

The *tst\_clock* program uses the *gfi status* command to determine if U1 has previously been tested using *gfi test*. If U1 has not been tested, a *gfi test* of U1 is performed. The *gfi status* command is then used to determine if the Clock and Reset outputs of U1 failed. If the outputs failed, the *abort\_test* program is executed and GFI troubleshooting is started. (See the Bus Buffer functional block for a discussion of *abort\_test*).

```
program tst_clock
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! FUNCTIONAL TEST of the CLOCK and RESET functional block.                       !
!                                                                                !
! This program tests the CLOCK and RESET functional block of the                 !
! Demo/Trainer. The gfi test command, I/O module and PROBE are used to         !
! perform the test.                                                             !
!                                                                                !
! TEST PROGRAMS CALLED:                                                         !
!   abort_test (ref-pin)                If gfi has an accusation               !
!                                       display the accusation else            !
!                                       create a gfi hint for the                !
!                                       ref-pin and terminate the test!         !
!                                       program (GFI begins trouble-            !
!                                       shooting).                               !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

print "\n!TESTING CLOCK & RESET Circuit"

if (gfi status "U1-10") = "untested" then
  gfi test "U1-10"
end if
if (gfi status "U1-12") = "bad" then abort_test ("U1-12")
if (gfi status "U1-10") = "bad" then abort_test ("U1-10")
if (gfi status "U1-13") = "bad" then abort_test ("U1-13")
if gfi test "U25-9" fails then abort_test ("U25-9")

print "CLOCK & RESET TEST PASSES"
end program
```

## Stimulus Programs and Responses

### 4.12.6.

Figure 4-112 is the stimulus program planning diagram for the Clock and Reset functional block. *frequency* is a general-purpose stimulus program used to measure the frequencies of various outputs around the Demo/Trainer UUT. *reset\_high* checks for a high-level Reset signal and *reset\_low* checks for a low-level Reset signal.

## Stimulus Program Planning



<b>PROGRAM: FREQUENCY</b>
MEASURES FREQUENCY
<b>MEASUREMENT AT:</b> U25-9,5 U1-10,13

<b>PROGRAM: RESET_LOW</b>
PROMPTS THE OPERATOR TO PRESS THE RESET KEY AND THEN CHECKS FOR A LOW LEVEL
<b>MEASUREMENT AT:</b> R10-1 R9-2

<b>PROGRAM: RESET_HIGH</b>
PROMPTS THE OPERATOR TO PRESS THE RESET KEY AND THEN CHECKS FOR A HIGH LEVEL
<b>MEASUREMENT AT:</b> U1-12

<b>PROGRAM: LEVELS</b>
MEASURES STATIC LEVELS
<b>MEASUREMENT AT:</b> J4-10,6 R34-1 DS1-2



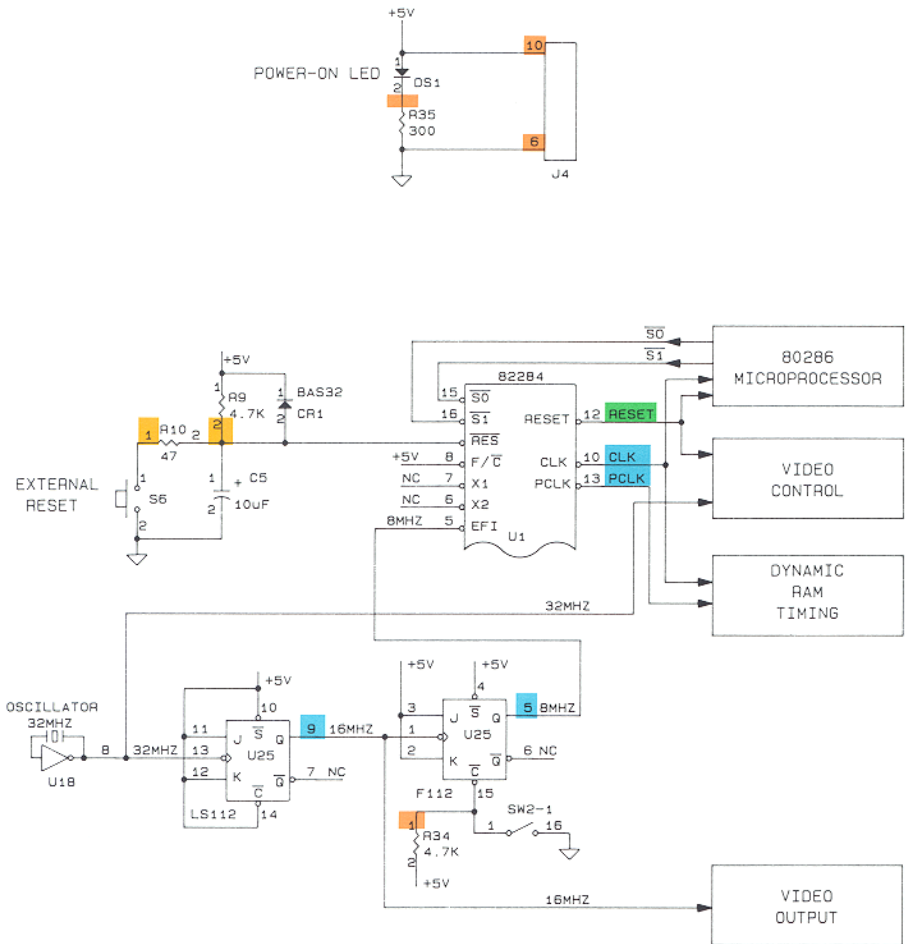


Figure 4-112: Clock and Reset Stimulus Program Planning

# Clock and Reset

```
program reset_high

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! STIMULUS PROGRAM characterizes the reset signal when high is active. !
! !!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Stimulus programs and response files are used by GFI to back-trace !
! from a failing node. The stimulus program must create repeatable UUT !
! activity and the response file contains the known-good responses for !
! the outputs in the UUT that are stimulated by the stimulus program. !
! !!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! TEST PROGRAMS CALLED: !
! (none) !
! !!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! GRAPHICS PROGRAMS CALLED: !
! (none) !
! !!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Local Constants Modified: !
! CARRAGE_RETURN Matches a carriage return input. !
! TRUE Value that is considered active TRUE!
! !!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Local Variables Modified: !
! input_str Input from keypad !
! state Level returned from measurement !
! pinnum The pin number used by level command!
! finished State of loop looking for condition !
! devname Measurement device !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Main Declarations !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

declare string CARRAGE_RETURN = ""
declare numeric TRUE = 1
declare string input_str
declare numeric state = 0
declare numeric pinnum = 1
finished = 0

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Main part of STIMULUS PROGRAM !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

! Let GFI determine the testing device.

if (gfi control) = "yes" then
  devname = gfi device
  measure_ref = gfi ref
  if measure_ref = "U1" then pinnum = 12
  if measure_ref = "U11" then pinnum = 38
```

*(continued on the next page)*

Figure 4-113: Stimulus Program (*reset\_high*)

```

    if measure_ref = "U13" then pinnum = 11
    if measure_ref = "U31" then pinnum = 35
    if measure_ref = "U19" then pinnum = 3
    if measure_ref = "U7" then pinnum = 15
  else
    devname = clip ref "U1"
    measure_ref = "U1"
  end if
  print "Stimulus Program RESET_HIGH"

! Setup measurement device and prompt operator.

  podsetup 'report power' "off"
  podsetup 'report forcing' "off"
  podsetup 'report intr' "off"
  podsetup 'report address' "off"
  podsetup 'report data' "off"
  podsetup 'report control' "off"
  reset device devname
  sync device devname, mode "int"
  podsetup 'report forcing' "off"
  t1up = open device "/term1", as "update"
  print on t1up ,"\07WHILE MEASURING, Press \1B[7mDemo UUT RESET\1B[0m key."
  print on t1up ,"Press 9100 ENTER key if test is stuck."

! Wait for a TRUE.  Leave program if <ENTER> key is pressed.

  loop until state = TRUE
    arm device devname \ readout device devname
    if devname = "/probe" then
      state = level device devname, type "async"
    else
      state = level device measure_ref, pin pinnum, type "async"
    end if
    if (poll channel t1up, event "input") = 1 then
      input on t1up ,input_str
      if input_str = CARRAGE_RETURN then return
    end if
  end loop

! Start response capture.  End when POD detects reset.

  arm device devname
  strobeclock device devname
  loop until finished = 1
    x = readstatus()
    if (x and $10) = $10 then
      strobeclock device devname
      finished = 1
    end if
    if (poll channel t1up, event "input") = 1 then
      input on t1up ,input_str
      if input_str = CARRAGE_RETURN then return
    end if
  end loop
  readout device devname
  print "\n\n"

end program

```

Figure 4-113: Stimulus Program (*reset\_high*) - *continued*



# Clock and Reset

---

STIMULUS PROGRAM NAME: RESET\_HIGH  
DESCRIPTION:

SIZE: 78 BYTES

Node	Learned	Response Data				Priority	
		With	SIG	Async Clk	Counter		
Signal Src			LVL	LVL	Mode	Counter Range	Pin
U1-12	PROBE	0001	1	0	TRANS		
U1-12	I/O MODULE	0001	1	0	TRANS		

Figure 4-114: Response File (*reset\_high*)

```

program reset_low

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! STIMULUS PROGRAM characterizes the reset signal when low is active.  !
!
! Stimulus programs and response files are used by GFI to backtrace
! from a failing node. The stimulus program must create repeatable UUT
! activity and the response file contains the known-good responses for
! the outputs in the UUT that are stimulated by the stimulus program.
!
! TEST PROGRAMS CALLED:
!
!   check_meas (device, start, stop, clock, enable)
!
!                                     Checks to see if the measure-
!                                     ment is complete using the
!                                     TL/1 checkstatus command. If
!                                     the measurement times out then
!                                     redisplay connect locations.
!
! GRAPHICS PROGRAMS CALLED:
!   (none)
!
! Local Constants Modified:
!   CARRAGE_RETURN           Matches a carriage return input.
!   TRUE                     Value that is considered active true!
!
! Local Variables Modified:
!   input_str                Input from keypad
!   state                    Level returned from measurement
!   pinnum                   The pin number used by level command!
!   finished                 State of loop looking for condition
!   devname                  Measurement device
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Main Declarations
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

declare string CARRAGE_RETURN = ""
declare string input_str
declare numeric state = 0
declare numeric TRUE = 4
declare numeric pinnum = 1
finished = 0

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Main part of STIMULUS PROGRAM
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

! Let GFI determine the testing device.

if (gfi control) = "yes" then
  devname = gfi device
  measure_ref = gfi ref

```

(continued on the next page)

Figure 4-115: Stimulus Program (*reset\_low*)

## Clock and Reset

```
    if measure_ref = "U1" then pinnum = 11
    if measure_ref = "U13" then pinnum = 13
    if measure_ref = "U19" then pinnum = 4
    if measure_ref = "U7" then pinnum = 15
else
    devname = clip ref "U1"
    measure_ref = "U1"
end if
print "Stimulus Program RESET_LOW"

! Setup measurement device and prompt operator.

podsetup 'report power' "off"
podsetup 'report forcing' "off"
podsetup 'report intr' "off"
podsetup 'report address' "off"
podsetup 'report data' "off"
podsetup 'report control' "off"
reset device devname
sync device devname, mode "int"
podsetup 'report forcing' "off"
tlup = open device "/term1", as "update"
print on tlup, "\07WHILE MEASURING, Press \1B[7mDemo UUT RESET\1B[0m key."
print on tlup, "Press 9100 ENTER key if test is stuck."

! Wait for a TRUE. Leave program if <ENTER> key is pressed.

loop until state = TRUE
    arm device devname \ readout device devname
    if devname = "/probe" then
        state = level device devname, type "async"
    else
        state = level device measure_ref, pin pinnum, type "async"
    end if
    if (poll channel tlup, event "input") = 1 then
        input on tlup ,input_str
        if input_str = CARRAGE_RETURN then return
    end if
end loop

! Start response capture. End when POD detects reset.

arm device devname
strobeclk device devname
loop until finished = 1
    x = readstatus()
    if (x and $10) = $10 then
        strobeclk device devname
        finished = 1
    end if
    if (poll channel tlup, event "input") = 1 then
        input on tlup ,input_str
        if input_str = CARRAGE_RETURN then return
    end if
end loop
readout device devname
print "\n\n"

end program
```

Figure 4-115: Stimulus Program (*reset\_low*) - continued

STIMULUS PROGRAM NAME: RESET\_LOW  
 DESCRIPTION:

SIZE: 146 BYTES

Node Signal Src	Learned With	SIG	Response Data			Priority Pin
			Async	Clk	Counter	
			LVL	LVL	Mode	Counter Range
U13-10	PROBE	0002	1	0	TRANS	
U13-10	I/O MODULE	0002	1	0	TRANS	
U19-4	I/O MODULE	0002	1	0	TRANS	
R10-1	PROBE	0002		1	0 TRANS	
R9-2	PROBE	0002		1	0 TRANS	
R9-2	I/O MODULE	0002		1	0 TRANS	

Figure 4-116: Response File (*reset\_low*)

## Clock and Reset

```
program frequency
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! STIMULUS PROGRAM to measure frequencies.                                !
!                                                                           !
! Stimulus programs and response files are used by GFI to backtrace      !
! from a failing node. The stimulus program must create repeatable UUT !
! activity and the response file contains the known-good responses for !
! the outputs in the UUT that are stimulated by the stimulus program. !
! This is a general purpose routine that can be used to characterize     !
! any free-running system clock, dot clock, etc...                       !
! When measuring frequency no stimulus is normally applied because the !
! signal begins running at power on.                                     !
!                                                                           !
! TEST PROGRAMS CALLED:                                                  !
!   (none)                                                                !
!                                                                           !
! GRAPHICS PROGRAMS CALLED:                                             !
!   (none)                                                                !
!                                                                           !
! Local Variables Modified:                                             !
!   devname                      Measurement device                       !
!                                                                           !
! Global Variables Modified:                                           !
!   (none)                                                                !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! FAULT HANDLERS:                                                       !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
handle pod_timeout_no_clk
end handle
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Main part of STIMULUS PROGRAM                                         !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

! Let GFI determine the measurement device.

if (gfi control) = "yes" then
  devname = gfi device
else
  devname = "/mod1"
end if
print "Stimulus Program FREQUENCY"

! Set addressing mode and setup measurement device.

podsetup 'report power' "off"
podsetup 'report forcing' "off"
podsetup 'report intr' "off"
podsetup 'report address' "off"
podsetup 'report data' "off"
podsetup 'report control' "off"
reset device devname
counter device devname, mode "freq"

! No stimulus is applied; response is frequency.

arm device devname           ! Start response capture.
readout device devname      ! End response capture.
end program
```

Figure 4-117: Stimulus Program (*frequency*)

STIMULUS PROGRAM NAME: FREQUENCY  
 DESCRIPTION:

SIZE: 370 BYTES

Node Signal Src	Learned With	SIG	Response Data			Counter Range	Priority Pin
			Async	Clk	Counter		
U1-10	PROBE		1	0	FREQ	7585000-8383000	U25-5
U1-10	I/O MODULE		1	0	FREQ	7585000-8383000	
U1-13	I/O MODULE		1	0	FREQ	3792000-4191000	U25-5
U25-5	PROBE		1	0	FREQ	7585000-8383000	
U25-5	I/O MODULE		1	0	FREQ	7585000-8383000	
U25-9	PROBE		1	0	FREQ	15170000-16760000	
U42-3	I/O MODULE		1	0	FREQ	379200-419100	
U42-7	I/O MODULE		1	0	FREQ	758500-838300	
U43-11	I/O MODULE		1	0	FREQ	63200-69800	
U56-12	PROBE		1	0	FREQ	63200-69800	
U56-12	I/O MODULE		1	0	FREQ	63200-69800	
U13-2	PROBE		1	0	FREQ	7585000-8383000	
U13-2	I/O MODULE		1	0	FREQ	7585000-8383000	
Y1-1	PROBE		1	0	FREQ	3670000-3700000	

Figure 4-118: Response File (*frequency*)

## Summary of Complete Solution for Clock and Reset

4.12.7.

The entire set of programs and files needed to test and GFI troubleshoot the Clock and Reset functional block is shown below. The format below is similar to a 9100A/9105A UUT directory (you could consider the functional block to be a small UUT), but in addition shows the use of each program and the location in this manual for each file.

### UUT DIRECTORY (Complete File Set for Clock and Reset)

#### Programs (PROGRAM):

TST_CLOCK	Functional Test	Section 4.12.5
FREQUENCY	Stimulus Program	Figure 4-117
RESET_HIGH	Stimulus Program	Figure 4-113
RESET_LOW	Stimulus Program	Figure 4-115
LEVELS	Stimulus Program	Figure 4-92

#### Stimulus Program Responses (RESPONSE):

FREQUENCY	Figure 4-118
RESET_HIGH	Figure 4-114
RESET_LOW	Figure 4-116
LEVELS	Figure 4-93

#### Node List (NODE):

NODELIST	Appendix B
----------	------------

#### Text Files (TEXT):

#### Reference Designator List (REF):

REFLIST	Appendix A
---------	------------

#### Compiled Database (DATABASE):

GFIDATA	Compiled by the 9100A
---------	-----------------------

**INTERRUPT CIRCUIT FUNCTIONAL BLOCK****4.13.****Introduction to Interrupt Circuits****4.13.1.**

Microprocessor-system interrupt circuits collect and prioritize the interrupt output of each circuit that has an interrupt-request output. These outputs come from circuits such as peripheral devices (keyboards, disk controllers, modems, printers) and dynamic RAM controllers. If there are enough interrupt signals, the system may use an interrupt controller to prioritize interrupts.

In some systems, the microprocessor can read a pointer to a branch address (called an "interrupt vector") from the microprocessor's external bus. These systems may have circuitry to generate the interrupt vector when the appropriate interrupt signal is asserted. Quite often, the vector-generation and interrupt-controller circuits are the same.

Figure 4-119 shows a typical interrupt circuit for a microprocessor system.

**Considerations for Testing and Troubleshooting****4.13.2.**

The Interrupt Circuit is part of a feedback loop. Address and data buses go out from the microprocessor to the various components in the UUT and interrupt lines come back from those components, through the Interrupt Circuit, to the microprocessor.

The pod can break this feedback loop by selectively ignoring the interrupt line to the pod. Particularly during troubleshooting, the interrupt line must be ignored so the 9100A/9105A is not interrupted while testing the interrupt circuitry.



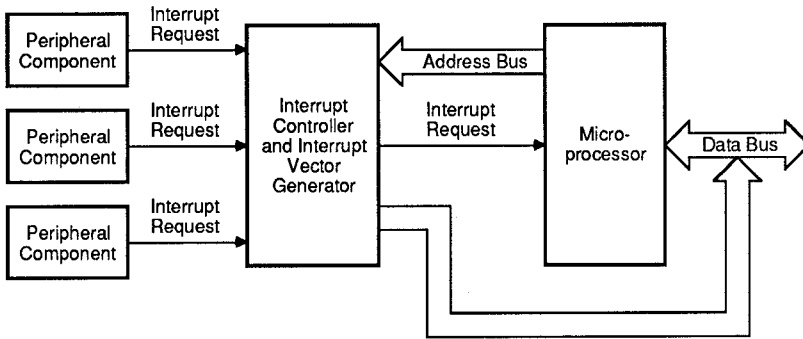


Figure 4-119: Typical Interrupt Circuit

The Interrupt Circuit can be tested by the following procedure:

1. Read or write to each component that can generate an interrupt so that an interrupt is generated.
2. After each interrupt is generated, check to see that the pod has detected the interrupt. If all interrupts are detected by the pod, the interrupt circuit is good.

If the microprocessor on your UUT has the ability to fetch an interrupt vector from its external bus, test the circuit that generates that vector by reading or writing to a component and thereby forcing that component to generate an interrupt. The interrupt vector should be the same address as the read or write address used to generate the interrupt.

Some pods (e.g. 8086, 8088, 80186, 80188, 80286, 68000) can read interrupt vectors. The '86-family and '88-family pods, for example, can read vectors automatically in response to an interrupt input from the pod to the UUT, or by command from the operator (TL/I programs that perform these functions are accessed with the POD key on the operator's keypad).

The availability of these automatic interrupt testing functions greatly eases the test procedures. With these functions, the procedure for testing interrupt vector generation circuits might work like this:

1. Configure the pod to capture an interrupt vector (this is usually called an "interrupt acknowledge cycle").
2. Write the interrupt vector to the interrupt controller or vector generator.
3. Perform some operation that causes the interrupt controller to interrupt the pod and place a vector on the UUT's bus. This operation may simply mean overdriving an input to the interrupt controller.

Troubleshooting the interrupt circuitry is accomplished by performing a procedure that causes each circuit with an interrupt request output to activate that output. Then signatures are recorded for all the nodes in the Interrupt Circuit. The steps to perform this are as follows:

1. Generate an interrupt on each interrupt request line that feeds into the interrupt circuit by performing the appropriate reads and writes.
2. Measure the signatures for each node in the Interrupt Circuit and compare to known-good signatures.
3. If an incorrect signature is found, follow that signal back towards its source.

You may need to disable the reporting of active interrupts by the pod when troubleshooting this circuit. If reporting is allowed and the interrupt is asserted, you may be unnecessarily bothered with "active interrupt" messages when the pod is used in stimulus operations. Section 4.15.2, "Forcing Lines", in this manual describes how to disable reporting of active interrupts.

### Interrupt Circuit Example

### 4.13.3.

Figure 4-120 shows the Interrupt Circuit for the Demo/Trainer UUT. This circuit uses two interrupts. The first, I/OINT, is configurable to be active when a character is transmitted or received through the serial port. The second, TIMER, is configurable to be active when the timer in the DUART IC (in the Serial I/O functional block) times out or when the output port toggles the bit in the output register connected to the TIMER output line.

### Keystroke Functional Test

### 4.13.4.

1. Use the SETUP MENU, EXEC, and READ keys with the commands below to disable interrupt trapping and to

initialize the Serial I/O functional block:

```
SETUP POD REPORT INTR ACTIVE OFF
EXECUTE RS232_INIT
READ ADDR 2016 =
... (ADDR OPTION: I/O BYTE)
```

2. Use the READ key with the commands below to check the status of interrupts in the UUT:

```
READ STATUS OF MICRO =
    (Should be C0 with no interrupts)
READ ADDR 30000 =
... (ADDR OPTION: MEMORY WORD)
    (Should be 27 with no interrupts)
```

3. Use the WRITE and READ keys with the following commands to force an interrupt on TIMER (by setting output OP3 low) and to check that the interrupt occurs:

```
WRITE DATA 0 TO ADDR 201A
... (ADDR OPTION: I/O BYTE)
WRITE DATA 8 TO ADDR 201C
... (ADDR OPTION: I/O BYTE)
READ STATUS OF MICRO =
    (Should be C8 with an interrupt)
READ ADDR 30000 =
... (ADDR OPTION: MEMORY WORD)
    (Should be 25 with a TIMER interrupt)
WRITE DATA 8 TO ADDR 201E
... (ADDR OPTION: I/O BYTE)
```

4. Use the WRITE and READ keys with the following commands to force an interrupt on I/OINT (by causing an interrupt from RS232) and to check that this interrupt occurs:

```
WRITE DATA 10 TO ADDR 200A
... (ADDR OPTION: I/O BYTE)
WRITE DATA 41 TO ADDR 2016
... (ADDR OPTION: I/O BYTE)
```

```
READ STATUS OF MICRO =  
    (Should be C8 with an interrupt)  
READ ADDR 30000 =  
    (Should be 22 with the I/OINT interrupt)  
... (ADDR OPTION: MEMORY WORD)  
WRITE DATA 0 TO ADDR 200A  
... (ADDR OPTION: I/O BYTE)
```

5. Re-enable interrupt trapping by using the SETUP MENU key to enter the following command:



```
SETUP POD REPORT INTR ACTIVE ON
```

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## Keystroke Functional Test



CONNECTION TABLE

STIMULUS	MEASUREMENT
<div style="text-align: center;">  <p>TEST ACCESS SOCKET</p> </div>	<div style="text-align: center;">  <p>TEST ACCESS SOCKET</p> </div>

STIMULUS AND MEASUREMENT TABLE

STIMULUS	MEASUREMENT	
	STATUS	ADDRESS 30000
NO INTERRUPTS TIMER INTERRUPT SERIAL INTERRUPT	C0 C8 C8	27 25 22



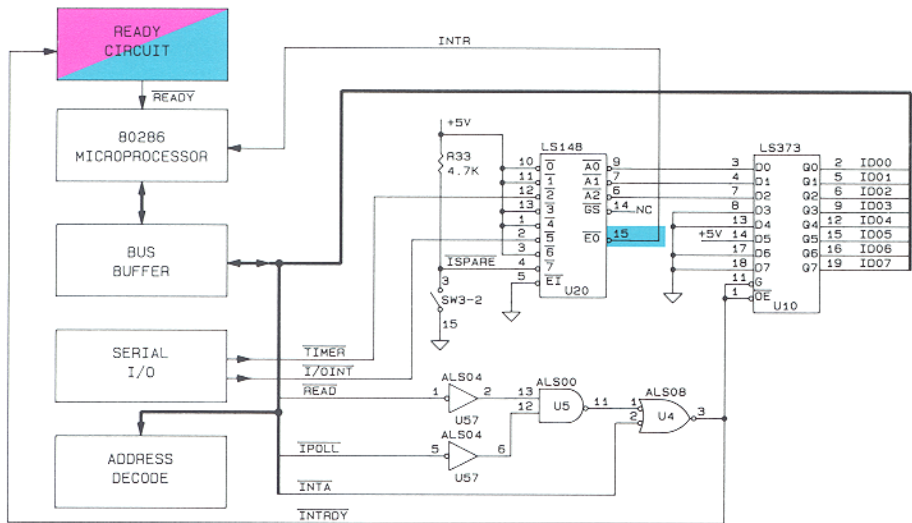


Figure 4-120: Interrupt Circuit Functional Test



## Programmed Functional Test

### 4.13.5.

The *tst intrpt* program is the programmed functional test for the Interrupt Circuit functional block. This program checks the interrupt poll register using the *gfi test* command. If the *gfi test* command fails, the *abort test* program is executed and GFI troubleshooting begins. (See the Bus Buffer functional block for a discussion of the *abort\_test* program).

```
program tst_intrpt
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! FUNCTIONAL TEST of the INTERRUPT functional block.                       !
!                                                                           !
! This program tests the INTERRUPT functional block of the Demo/Trainer.    !
! The gfi test command and I/O module are used to perform the test.        !
!                                                                           !
! TEST PROGRAMS CALLED:                                                     !
!   abort_test (ref-pin)           If gfi has an accusation                !
!                                   display the accusation else             !
!                                   create a gfi hint for the               !
!                                   ref-pin and terminate the test!         !
!                                   program (GFI begins trouble-           !
!                                   shooting).                               !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

print "\n!TESTING INTERRUPT Circuit"

podsetup 'report intr' "off"
if gfi test "U10-1" fails then abort_test("U10-1")

print "INTERRUPT TEST PASSES"
end program
```

## Stimulus Programs and Responses

### 4.13.6.

Figure 4-121 is the stimulus program planning diagram for the Interrupt Circuit functional block. The *decode* stimulus program performs an access at each decoded address space. The *t1l\_lvl* stimulus program transmits a character out the serial port and measures signals using TTL threshold levels. The *interrupt* stimulus program generates interrupts in the Serial I/O circuit and measures interrupt lines.

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## Stimulus Program Planning



<b>PROGRAM: CTRL_OUT3</b>
PERFORMS AN ACCESS FOR EACH DECODED BLOCK
<b>MEASUREMENT AT:</b>  U4-3

<b>PROGRAM: INTERRUPT</b>
EXECUTES RS232_INIT AND EXERCISES INTERRUPT LINES
<b>MEASUREMENT AT:</b>  U10-2,5,6,9,12,15,16,19 U20-6,7,9,15 R33-1 U5-11

<b>PROGRAM: DECODE</b>
PERFORMS AN ACCESS FOR EACH DECODED BLOCK
<b>MEASUREMENT AT:</b>  U57-2,6 U5-11 U4-3



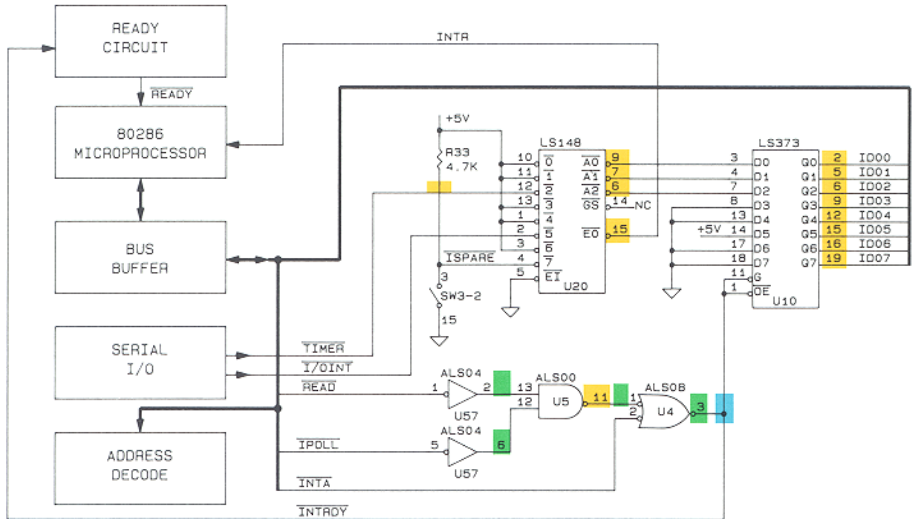


Figure 4-121: Interrupt Circuit Stimulus Program Planning

# Interrupt Circuit

program interrupt

```
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! STIMULUS PROGRAM to exercise the interrupt circuitry.                               !
!                                                                                       !
! Stimulus programs and response files are used by GFI to backtrace                   !
! from a failing node. The stimulus program must create repeatable UUT               !
! activity and the response file contains the known-good responses for               !
! the outputs in the UUT that are stimulated by the stimulus program.               !
!                                                                                       !
! This stimulus program sets the DUART to cause an interrupt when data               !
! is written to the transmit register. Immediately after the write to               !
! the register the interrupt vector is read from the bus (read @ 30000).            !
!                                                                                       !
! TEST PROGRAMS CALLED:                                                                !
!   (none)                                                                              !
!                                                                                       !
! GRAPHICS PROGRAMS CALLED:                                                            !
!   rs232_init()                               This is the initialization for       !
!                                               the DUART which contains a       !
!                                               timer used for interrupts.         !
!                                                                                       !
! Local Variables Modified:                                                            !
!   devname                                     Measurement device                    !
!                                                                                       !
! Global Variables Modified:                                                            !
!   (none)                                                                                !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!
! Main part of STIMULUS PROGRAM                                                       !
!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!!

! Let GFI determine the measurement device.

  if (gfi control) = "yes" then
    devname = gfi device
  else
    devname = "/mod1"
  end if
  print "Stimulus Program INTERRUPT"

! Set addressing mode and setup measurement device.

  reset device devname
  execute rs232_init()
  write addr $200A, data $10 ! Set interrupt on transmit - no loopback
  setspace space (getspace space "i/o", size "byte")
  sync device devname, mode "pod"
  sync device "/pod", mode "data"
  threshold device "/probe", level "ttl"
```

*(continued on the next page)*

Figure 4-122: Stimulus Program (*interrupt*)

```
! Present stimulus to UUT.

arm device devname          ! Start response capture.
write addr $2016, data $55  !   Txd port B
setspace space (getspace space "memory", size "word")
read addr $30000           ! read the interrupt vector onto the bus.
setspace space (getspace space "i/o", size "byte")
write addr $2016, data $D   !   Txd port B
setspace space (getspace space "memory", size "word")
read addr $30000
setspace space (getspace space "i/o", size "byte")
write addr $201C, data $FF
setspace space (getspace space "memory", size "word")
read addr $30000
setspace space (getspace space "i/o", size "byte")
write addr $201E, data $FF  !   Pulse timer interrupt.
setspace space (getspace space "memory", size "word")
read addr $30000
readout device devname     ! End response capture.

end program
```

Figure 4-122: Stimulus Program (*interrupt*) - *continued*

# Interrupt Circuit

STIMULUS PROGRAM NAME: INTERRUPT  
DESCRIPTION:

SIZE: 660 BYTES

Node Signal Src	Learned With	SIG	Response Data				Counter Range	Priority Pin
			Async LVL	Clk LVL	Counter Mode	Counter Range		
U10-6	PROBE	00AB	1 0	1 0	TRANS	4		
U10-6	I/O MODULE	00AB	1 0	1 0	TRANS	4		
U10-2	PROBE	00AB	1 0	1 0	TRANS	4		
U10-2	I/O MODULE	00AB	1 0	1 0	TRANS	4		
U10-5	PROBE	005F	1 0	1 0	TRANS	2		
U10-5	I/O MODULE	005F	1 0	1 0	TRANS	2		
U10-9	PROBE	002A	1 0	1 0	TRANS	5		
U10-9	I/O MODULE	002A	1 0	1 0	TRANS	5		
U10-12	PROBE	008B	1 0	1 0	TRANS	5		
U10-12	I/O MODULE	008B	1 0	1 0	TRANS	5		
U10-15	PROBE	005F	1 0	1 0	TRANS	2		
U10-15	I/O MODULE	005F	1 0	1 0	TRANS	2		
U10-16	PROBE	008B	1 0	1 0	TRANS	5		
U10-16	I/O MODULE	008B	1 0	1 0	TRANS	5		
U10-19	PROBE	000A	1 0	1 0	TRANS	6		
U10-19	I/O MODULE	000A	1 0	1 0	TRANS	6		
U20-6	I/O MODULE	0000	1 0	0	TRANS	2		
U20-7	I/O MODULE	00FE	1	1	TRANS	0		
U20-9	I/O MODULE	0000	1 0	0	TRANS	2		
U20-15	PROBE	00FE	1 0	1	TRANS	2		
U20-15	I/O MODULE	00FE	1 0	1	TRANS	2		
R33-1	PROBE	00FE	1	1	TRANS	0		
R33-1	I/O MODULE	00FE	1	1	TRANS	0		
U5-11	I/O MODULE	00AB	1 0		TRANS			

Figure 4-123: Response File (*interrupt*)

## Summary of Complete Solution for Interrupt Circuit

4.13.7.

The entire set of programs and files needed to test and GFI troubleshoot the Interrupt Circuit functional block is shown below. The format below is similar to a 9100A/9105A UUT directory (you could consider the functional block to be a small UUT), but in addition shows the use of each program and the location in this manual for each file.

### UUT DIRECTORY (Complete File Set for Interrupt Circuit)

#### Programs (PROGRAM):

TST_INTRPT	Functional Test	Section 4.13.5
CTRL_OUT3	Stimulus Program	Figure 4-103
INTERRUPT	Stimulus Program	Figure 4-122
DECODE	Stimulus Program	Figure 4-108

#### Stimulus Program Responses (RESPONSE):

CTRL_OUT3	Figure 4-104
INTERRUPT	Figure 4-123
DECODE	Figure 4-109

#### Node List (NODE):

NODELIST	Appendix B
----------	------------

#### Text Files (TEXT):

#### Reference Designator List (REF):

REFLIST	Appendix A
---------	------------

#### Compiled Database (DATABASE):

GFIDATA	Compiled by the 9100A
---------	-----------------------



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## READY CIRCUIT FUNCTIONAL BLOCK

4.14.

### Introduction to Ready Circuits

4.14.1.

Some peripheral components have different (slower) timing than the microprocessor. To accommodate these components, wait states (extra clock cycles) are added to the read and write bus cycles. The number of wait states inserted is typically controlled by an input to the microprocessor called Wait, Ready, or DTACK; in this discussion, we will call it the Ready signal.

Many microprocessor systems have a circuit that generates the Ready signal in response to the selection of a peripheral component. The circuit (Figure 4-124) typically consists of a counter and/or a state machine that uses the microprocessor clock. The inputs to the state machine include a strobe signal from the microprocessor (to indicate that a bus cycle has started) and the various decoder outputs that select the components needing wait states.

In a given bus cycle, the state machine typically recognizes the assertion of the microprocessor strobe signal, and looks at the decoder signals to determine which component is being selected. The state machine then asserts Ready for the appropriate number of clock cycles.

### Considerations for Testing and Troubleshooting

4.14.2.

Ready circuits often involve multiple feedback loops between the microprocessor and the ROM, RAM timing, and video control circuits. Since these feedback loops may need to remain unbroken while testing memory and/or video circuits, the Ready circuit is tested separately. Here is a good way to test the Ready circuit:

1. Break the feedback loop by overdriving the lines that form the feedback loop.

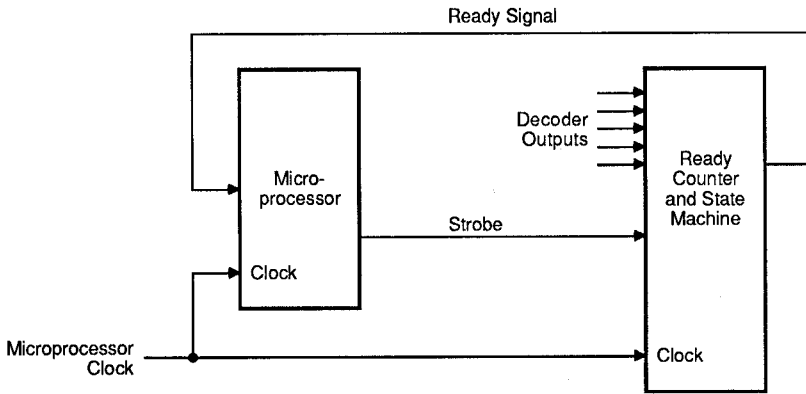


Figure 4-124: Typical Ready Circuit

2. Exercise the rest of the inputs using microprocessor reads and writes.
3. Measure the output of the loop.

A second approach is to use one I/O module to overdrive all the inputs and another I/O module (or another clip on the same I/O module) to measure the Ready output to the microprocessor.

Test each IC in the circuit individually, using the following procedure:

1. Clip the I/O module onto the IC.
2. Synchronize and arm the I/O module (see the *Technical User's Manual* for this procedure).
3. Run a stimulus procedure to make each output go high and low (this may mean overdriving another part of the circuit with another I/O module clip).
4. Use the SHOW I/O MOD command on the I/O MOD key (operator's keypad) to observe signatures on each pin of the IC.
5. Write down the signatures gathered from each pin on the IC, both inputs and outputs.

Compare the signatures gathered on the suspect UUT to those from a known-good UUT to determine which pins are bad.

Test the timing properties of the state machine that actually generates the Ready signal. You can do this with the external Start, Stop, and Clock lines on the I/O module or clock module to begin timing the wait states. Connect the external Clock line to the Ready-circuit's clock input (the microprocessor clock). Connect the Start line to the signal that starts the wait state generation. Set the Stop count to the proper number of clock cycles to verify that the wait state becomes active at the proper time. If the Stop count is set properly, decreasing its value by 1

from the proper value should show that the wait state does not become active and using the proper value should show that the wait state is active.

Again, compare the responses gathered on the suspect UUT to those from a known-good UUT to determine which pins are bad.

If the outputs of the ICs are bad and the inputs are good, suspect the IC and/or suspect shorts on the output signal paths. If the inputs are bad as well, trace back toward the microprocessor. If your UUT has address latches or buffers, perform a similar test on them.

You may need to disable the Ready input to the pod and turn reporting of forcing lines off when troubleshooting this circuit. If the Ready input to the pod is enabled, and Ready is not asserted for a long enough time due to testing operations, the pod may timeout if it is being used in the stimulus operation. Section 4.15.4, "Forcing Lines", in this manual describes how to disable the Ready input to the pod.

### Ready Circuit Example

#### 4.14.3.

The Ready Circuit for the Demo/Trainer UUT is shown in Figure 4-125. The microprocessor does not complete the current bus cycle until an active Ready signal (a low) is received from the Ready Circuit. Any circuit addressed to be read by the microprocessor must return such a Ready signal. Some circuits (ROM0, ROM1, and Interrupt) set SRDY low right away and the read is completed on the next clock cycle. Other circuits (Parallel I/O, Serial I/O, and Video Control) cannot match the speed of the microprocessor and add three wait states for proper timing. In addition, Dynamic RAM Timing may insert wait states in order to delay until RAM refresh finishes, and Video RAM may insert wait states to synchronize the microprocessor with video scan sequences.

The microprocessor drives address lines, which go to address decoding, and the outputs of address decode are inputs to the

Ready Circuit. The output of the Ready Circuit is an input to the microprocessor, which forms a feedback loop. The pod is able to break this feedback loop by ignoring and disabling the Ready input.

The Ready Circuit has a second, more troublesome feedback loop. The Ready output, U1-4, feeds back as an input to the Ready Circuit at U4-12. This second feedback loop must be broken in order to perform testing or troubleshooting on the Ready Circuit.

### Keystroke Functional Test

4.14.4.

The functional test for the Ready Circuit uses two I/O module clips. One clip is used for measurement and the other clip is used to overdrive Ready Circuit inputs (to break the Ready Circuit feedback loop).

In the following procedure use one clip module to measure U1-4, U4-6, and U17-11 outputs. Use the second clip module as prompted by the program.

#### Part A:

1. Use a 20-pin clip module on side A of I/O module 1 and a 14-pin clip module on side B as the second clip of I/O module 1 to check the Ready Circuit output.
2. Use the EXEC and I/O MOD keys with the commands below for U1 and U4. The correct measurements for each pin are shown in the response table of Figure 4-125.

```
EXECUTE UUT DEMO PROGRAM READY_1
```

The program will prompt:

```
Enter ref name (Choose U1, U4, U14 OR U15)
```

Type in U1 and press the ENTER key.

Follow the instructions to clip U1 and press the Ready button on the clip module. Then clip U4 and press the Ready button on its clip module.

```
SHOW I/O MOD 1 PIN 4 CAPTURED RESPONSES  
SHOW I/O MOD 1 PIN 26 CAPTURED RESPONSES
```

### **NOTE**

*The SHOW command requires a clip module pin number rather than a part pin number. This requires you to translate part pin numbers to clip module pin numbers (see Appendix B of the Technical User's Manual). For your convenience, this translation has been done for you in this example, and the results are shown in the "I/O MOD PIN" column of the response table in Figure 4-125.*

### **Part B:**

1. Use a 14-pin clip module on side B of I/O module 1 to check the Ready Circuit.
2. Use the EXEC and I/O MOD keys with the commands below for U4. The correct measurement for this step is shown in response table #1 of Figure 4-126.

```
EXECUTE UUT DEMO PROGRAM READY_2
```

The program will prompt:

```
Enter ref name (Choose U1, U4, U5, U6 or U17)
```

Type in U4 and press the ENTER key.

Follow the instructions to clip U4 and press the Ready button on the clip module.

SHOW I/O MOD 1 PIN 26 CAPTURED RESPONSES

3. Use a 14-pin clip module on side A of I/O module 1 to check the Ready Circuit.
4. Use the EXEC and I/O MOD keys with the commands below for U4. The correct measurement for this step is shown in response table #2 of Figure 4-126.

EXECUTE UUT DEMO PROGRAM READY\_3

The program will prompt:

Enter ref name (Choose U1, U4, U5 or U6)

Type in U4 and press the ENTER key.

Follow the instructions to clip U4 and press the Ready button on the clip module.

SHOW I/O MOD 1 PIN 26 CAPTURED RESPONSES

### Part C:

1. Use a 14-pin clip module on side A of I/O module 1 and a 20-pin clip module on side B as the second clip of I/O module 1 to check the Ready Circuit.
2. Use the EXEC and I/O MOD keys with the commands below for U5. The correct measurement for each pin is shown in the response table of Figure 4-127.

EXECUTE UUT DEMO PROGRAM READY\_4

The program will prompt:

Enter ref name (Choose U4, U5 or U17)



Type in U5 and press the ENTER key.

Follow the instructions to clip U5 and press the Ready button on the clip module.

Then clip U17 using the second clip module and press its Ready button.

```
SHOW I/O MOD 1 PIN 3 CAPTURED RESPONSES
```

### Part D:

1. Use a 20-pin clip module on side A of I/O module 1 to check the Ready Circuit I/O wait state generator.
2. Use the EXEC and I/O MOD keys with the commands below for U17. The correct measurement for this step is shown in response table #1 of Figure 4-128.

```
EXECUTE UUT DEMO PROGRAM READY_5
```

The program will prompt:

```
Enter ref name (Choose U5 or U17)
```

Type in U17 and press the ENTER key.

Follow the instructions to clip U17 and press the Ready button on the clip module.

```
SHOW I/O MOD 1 PIN 17 CAPTURED RESPONSES
```

3. Use a 20-pin clip module on side A of I/O module 1 to check the Ready Circuit I/O wait state generator.

4. Use the EXEC and I/O MOD keys with the commands below for U17. The correct measurement responses for each step are shown in response table #2 of Figure 4-128.

```
EXECUTE UUT DEMO PROGRAM READY_6
```

The program will prompt:

```
Enter ref name (Choose U5 or U17)
```

Type in U17 and press the ENTER key.

Follow the instructions to clip U17 and press the Ready button on the clip module.

```
SHOW I/O MOD 1 PIN 17 CAPTURED RESPONSES
```